Micron Xccela™ Flash Memory

1.8V, Octal I/O, 4KB, 32KB, 128KB, Sector Erase
MT35XU512ABA

Features

- SPI-compatible Xccela™ bus interface
  - Octal DDR protocol
  - Extended-SPI protocol with octal commands
- Xccela™ is JEDEC xSPI standard compliant
- Single and double transfer rate (SDR/DDR)
- Clock frequency
  - 166 MHz (MAX) in SDR (166 MB/s)
  - 200 MHz (MAX) in DDR (400 MB/s) with DQS
- Execute-in-place (XIP)
- PROGRAM/ERASE SUSPEND operations
- Volatile and nonvolatile configuration settings
- Software reset
- Reset pin available
- 3-byte and 4-byte address modes – enable memory access beyond 128Mb
- Dedicated 64-byte OTP area outside main memory
  - Readable and user-lockable
  - Permanent lock with PROGRAM OTP command
- Erase capability
  - Bulk erase
  - Sector erase 128KB uniform granularity
  - Subsector erase 4KB, 32KB granularity
- Security and write protection
  - Volatile and nonvolatile locking and software write protection for each 128KB sector
  - Nonvolatile configuration locking
  - Password protection
  - Protection management register offering enhanced security features
  - Hardware write protection: nonvolatile bits (BP[3:0] and TB) define protected area size
  - Program/erase protection during power-up
  - CRC detects accidental changes to raw data
- Electronic signature
  - JEDEC-standard 3-byte signature
  - Extended device ID: two additional bytes identify device factory options
- JESD47I-compliant
  - Minimum 100,000 ERASE cycles per sector
  - Data retention: 20 years (TYP)

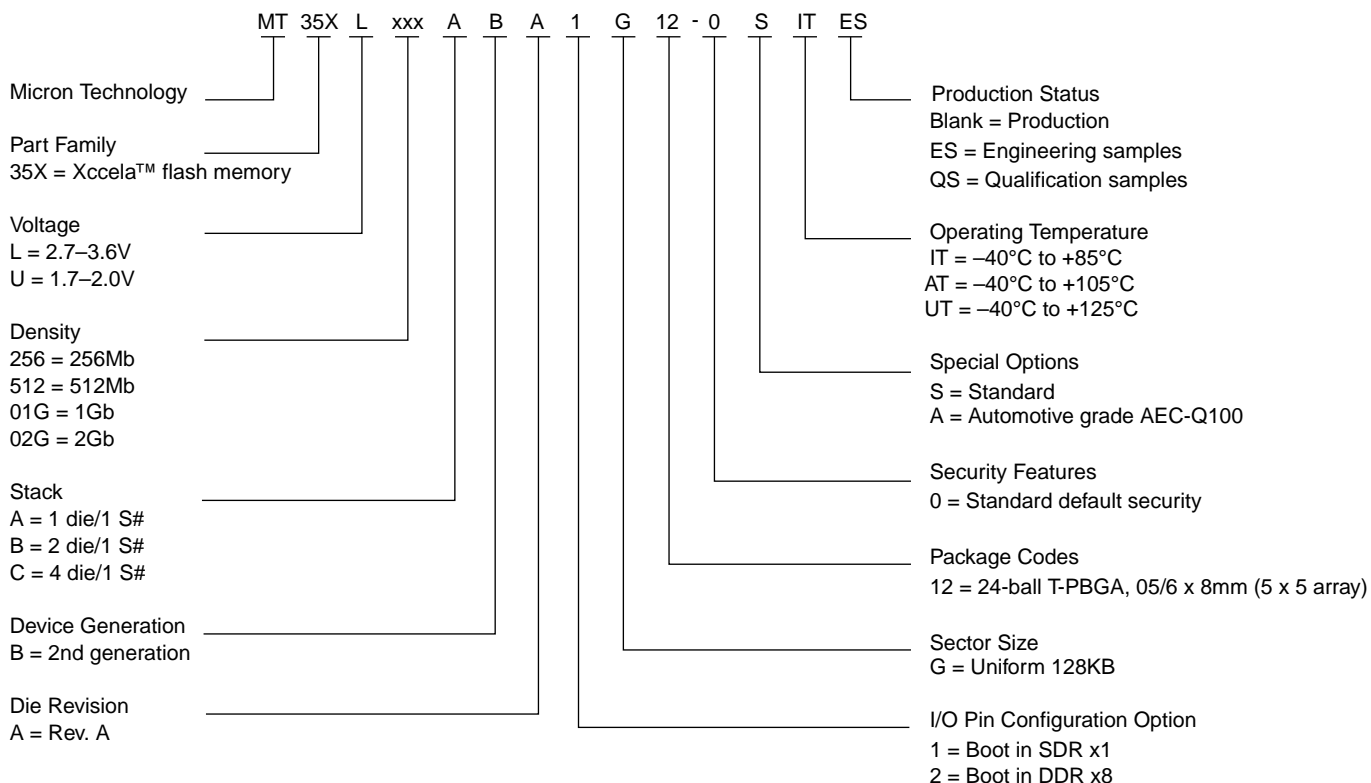| Options	Marking
• Voltage	
– 1.7–2.0V	U
• Density	
– 512Mb	512
• Device stacking	
– Monolithic	A
• Device Generation	B
• Die revision	A
• Configuration	
– Boot in SDR x1	1
– Boot in DDR x8	2
• Sector Size	
– 128KB	G
• Packages – JEDEC-standard, RoHS-compliant	
– 24-ball T-PBGA 05/6mm x 8mm (5 x 5 array)	12
• Security features	
– Standard security	0
• Special options	
– Standard	S
– Automotive	A
• Operating temperature range	
– From –40°C to +85°C	IT
– From –40°C to +105°C	AT
– From –40°C to +125°C	UT

Part Number Ordering

Micron **Xccela** flash devices are available in different configurations and densities. Verify valid part numbers by using Micron's part catalog search at www.micron.com. To compare features and specifications by device type, visit www.micron.com/products. Contact the factory for devices not found.

Figure 1: Part Number Ordering Information

```
MT  35X  L  xxx  A  B  A  1  G  12 - 0  S  IT  ES
```

Micron Technology

Part Family
35X = Xccela™ flash memory

Voltage
L = 2.7–3.6V
U = 1.7–2.0V

Density
256 = 256Mb
512 = 512Mb
01G = 1Gb
02G = 2Gb

Stack
A = 1 die/1 S#
B = 2 die/1 S#
C = 4 die/1 S#

Device Generation
B = 2nd generation

Die Revision
A = Rev. A

Production Status
Blank = Production
ES = Engineering samples
QS = Qualification samples

Operating Temperature
IT = −40°C to +85°C
AT = −40°C to +105°C
UT = −40°C to +125°C

Special Options
S = Standard
A = Automotive grade AEC-Q100

Security Features
0 = Standard default security

Package Codes
12 = 24-ball T-PBGA, 05/6 x 8mm (5 x 5 array)

Sector Size
G = Uniform 128KB

I/O Pin Configuration Option
1 = Boot in SDR x1
2 = Boot in DDR x8

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Device Description

The Micron **Xccela** flash is a high-performance, multiple I/O, SPI-compatible flash memory device. It features a high-speed, low pin count **Xccela** bus interface with a DDR clock frequency of up to 200 MHz for 1.8V parts and up to 133 MHz for 3.0 V parts, using eight I/O signals and a data strobe (DQS pin).

SUSPEND and RESUME commands provide the ability to pause and resume PROGRAM/ERASE operations. Nonvolatile and volatile configuration registers enable respective default and temporary settings such as READ operation dummy clock cycles and wrap modes, memory protection, output buffer impedance, SPI protocol type, and XiP mode.

Memory is organized as uniform 128KB sectors, 4KB and 32KB sub-sectors, and 256 byte pages. The device also includes a 64-byte one-time-programmable (OTP) memory area that can be permanently locked.

Direct boot in octal DDR protocol provides high performance and ease of use, enabling communication between the host and flash device without need to configure extended SPI protocol operations. However, the device still supports both extended SPI and octal DDR protocols to ensure legacy system support and an easy migration path. The extended SPI protocol supports address and data transmission on one or eight data lines, depending on the command.

Note: XIP feature is supported in extended-SPI because its commands are sent through DQ0 only.

Information in octal DDR protocol is always transmitted by eight data lines on both rising and falling clock edges. Most legacy x1 SPI commands are supported but require only one clock cycle because the command is latched on both the rising and falling edges of the clock. Address cycles are fixed at 4-byte READ operations from the flash array.

The host does not need to drive DQS during the input operation to the memory. The data input (DQ) to the memory still relies on clock (C) to latch all address and data operations. Most register outputs require dummy clock cycles due to the critical timing from command decoding. With the help of DQS for data latching, the number of dummy clocks is transparent to the host.

Block Diagram

Figure 2: Block Diagram – Components and Signals
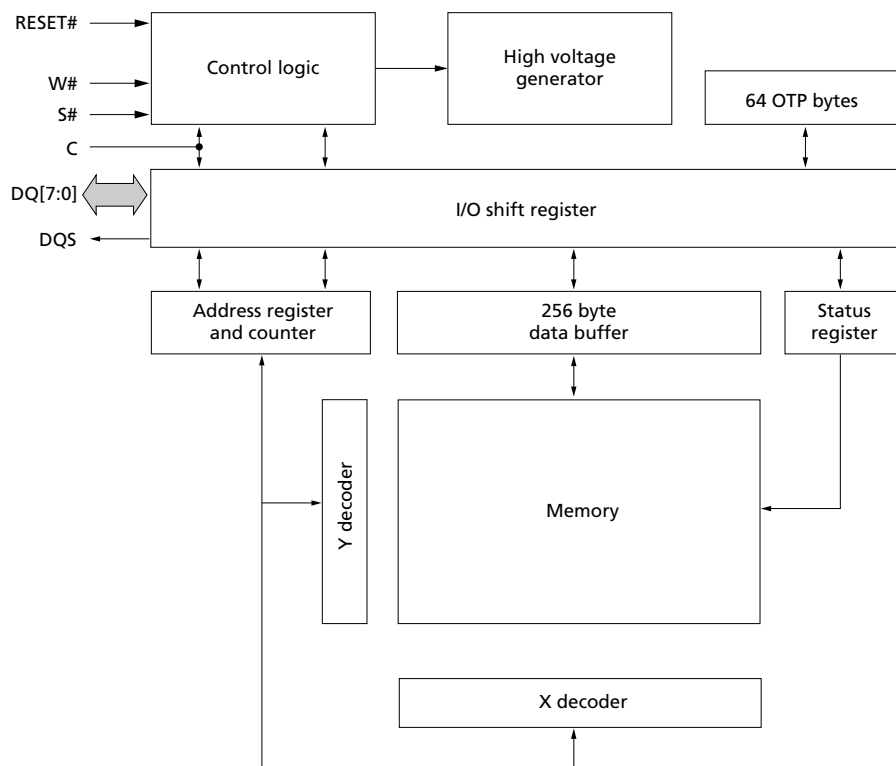
Note: 1. Each page of memory can be individually programmed, but the device is not page-erasable.

Device Logic Diagram

Figure 3: Logic Diagram
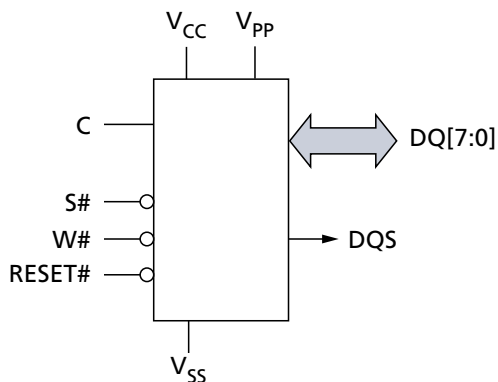
Advanced Security Protection

The device offers an advanced security protection scheme where each sector can be independently locked by either volatile or nonvolatile locking features. The nonvolatile locking configuration can also be locked, as well password-protected. See Block Protection Settings and Security Registers on page 24 for more details.

Signal Assignments

Figure 4: 24-Ball TBGA, 5 x 5 (Balls Down)
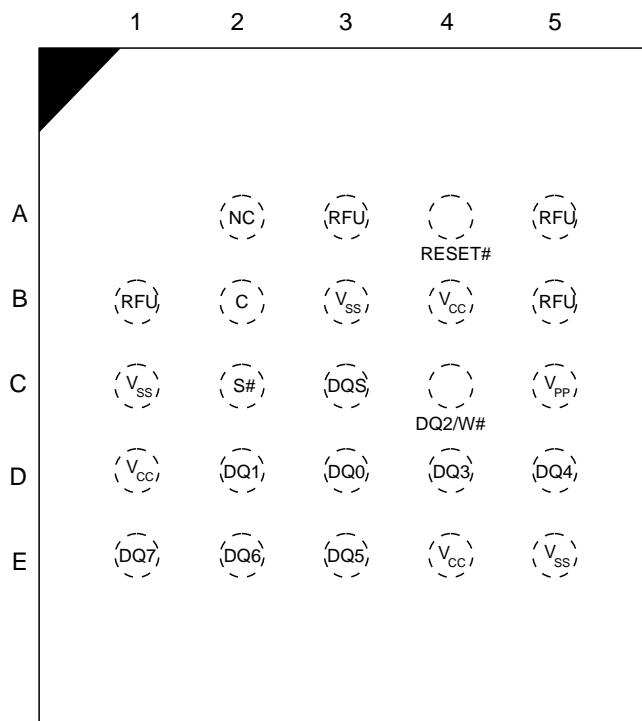
Note: 1. See Part Number Ordering Information for complete package names and details.

Signal Descriptions

The table below is a comprehensive list of device signals. All signals listed may not be supported. See Signal Assignments for device-specific information.

Table 1: Signal Descriptions

Symbol	Type	Description
C	Input	**Clock:** Provides timing for the serial interface. Command, address, or data inputs are latched on the rising edge of C. Data is shifted out on the falling edge of C.
S#	Input	**Chip select:** When S# is LOW, device is selected and in active power mode. Operations are initiated on the falling edge of S#. When S# is HIGH, device is deselected, DQ pins are tri-stated, and unless an internal WRITE operation is in progress, device enters standby mode.
RESET#	Input	**RESET:** Resets device to its default settings, such as after a volatile configuration register setting which then requires a return to the device default setting. Reset is optional when device settings are fixed by nonvolatile configuration register settings and always synchronized with the host. This pad is internally tied to weak pull-up so the pin can be floated.
W#	Input	**Write protect:** This input signal is used to freeze the status register in conjunction with the enable/disable bit of the status register. When the enable/disable bit of the status register is set to 1 and the W# signal is driven LOW, the status register nonvolatile bits become read-only and the WRITE STATUS REGISTER operation will not be executed. During the extended-SPI protocol with OCTAL READ/PROGRAM instructions, and during octal DDR protocol, this pin functions are an input/output (DQ2 functionality). This signal does not have internal pull-ups, it should not be left floated and must be driven, even if none of W#/DQ2 function is used.
DQ[7:0]	I/O	**Serial I/O:** Bidirectional signals that transfer address, data, and command information. In extended-SPI protocol, DQ0 functions as input and DQ1 as output. DQ[7:2] are not used. In octal protocol, input/output on DQ[7:0] depends on the command. Input can be latched on the rising edge of C (SDR) or on both edges of C (DDR). Data can be shifted out on the falling edge of C (SDR) or on both edges of C (DDR). In octal DDR, DQ[7:0] always function as I/O, input is latched on both edges of C, and output is shifted out on both edges of C. DQ2 is used also as write protection control.
DQS	Output	**Data strobe:** Indicates output data valid for DDR modes and is required to support high speed data output. Not required in extended-SPI protocol except to achieve high frequency for specific DDR commands. Used for READ but not for WRITE operations. Configured by nonvolatile and volatile configuration register bit 5 at address 00h. When enabled, DQS is driven to ground at S# LOW and until the device is driving output data, in which case DQS toggles to synchronize data output. When not enabled, DQS is not driven.
V_{CC}	Supply	**Supply voltage:** Core and I/O supply.
V_{PP}	Supply	**Supply voltage:** If V_{PP} is in the voltage range of V_{PPH}, the signal acts as an additional power supply for programming operation, as defined in the Operating Conditions table. The V_{PP} pad will be internally pulled up to V_{CC}, so customer can leave V_{PP} pin floated if not used.
V_{SS}	Supply	**Ground:** Core and I/O ground connection. V_{SS} is the reference for the V_{CC} supply voltage.
DNU	–	**Do not use:** Do not connect to any other signal, or power supply; must be left floating.
RFU	–	**Reserved for future use:** Reserved by Micron for future device functionality and enhancement. Recommend that these should be left floating. May be connected internally, but external connections will not affect operation.
NC	–	**No connect :** No internal connection; can be driven or floated.

Package Dimensions – Package Code: 12

Figure 5: 24-Ball T-PBGA (5 x 5 ball grid array) – 6mm x 8mm
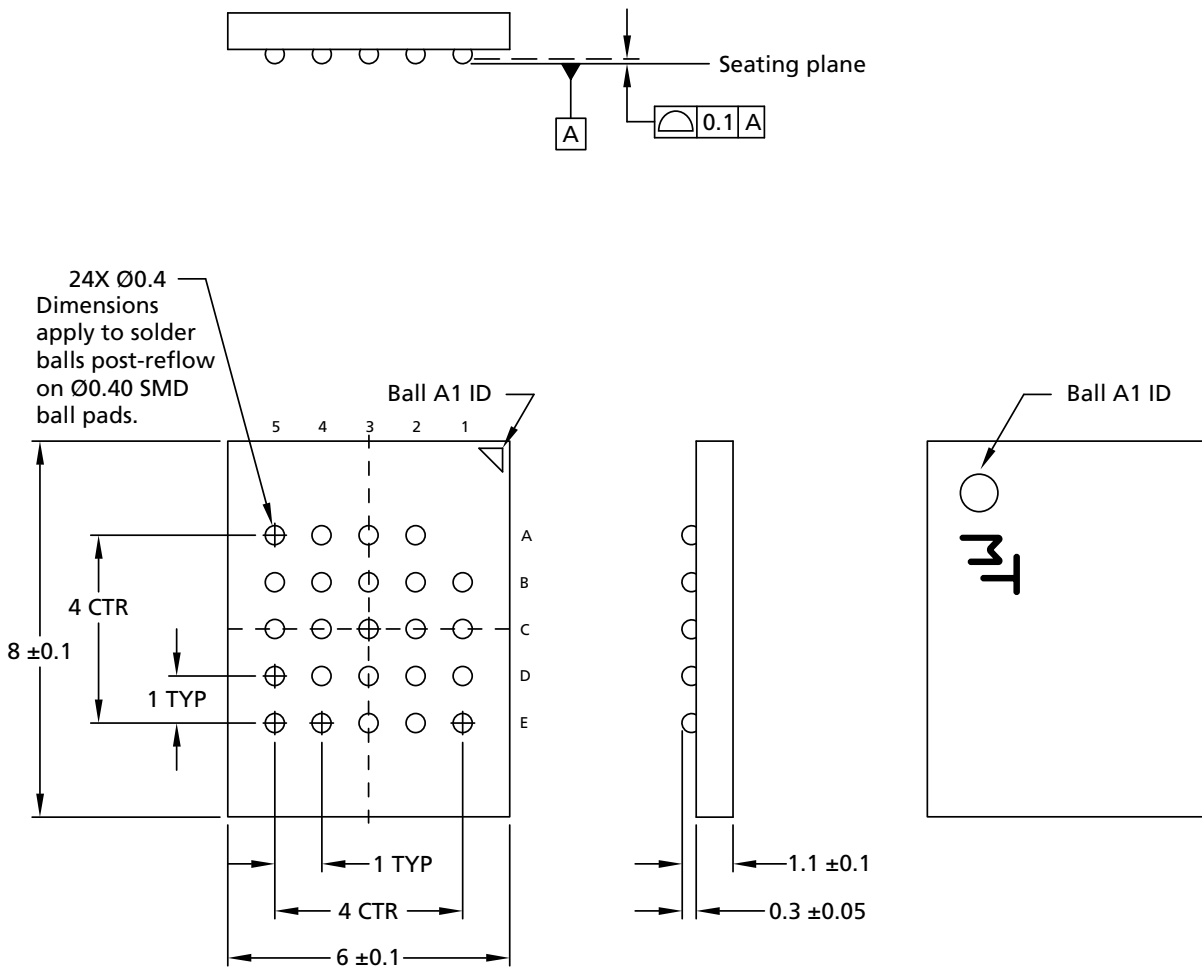
Notes: 1. All dimensions are in millimeters.
2. See Part Number Ordering Information for complete package names and details.

Memory Map – 512Mb Density

Table 2: Sectors[511:0]

Sector	Subsector (4KB)	Address Range	
		Start	**End**
511	16,383	03FF F000h	03FF FFFFh
	16,353	03FE 1000h	03FE 1FFFh
	16,352	03FE 0000h	03FE 0FFFh
1	63	0003 F000h	0003 FFFFh
	33	0002 1000h	0002 1FFFh
	32	0002 0000h	0002 0FFFh
0	31	0001 F000h	0001 FFFFh
	1	0000 1000h	0000 1FFFh
	0	0000 0000h	0000 0FFFh

Status Register

Status register bits can be read from or written to using READ STATUS REGISTER or WRITE STATUS REGISTER commands, respectively. When the status register enable/disable bit (bit 7) is set to 1 and W# is driven LOW, the status register nonvolatile bits become read-only and the WRITE STATUS REGISTER operation will not execute. The only way to exit this hardware-protected mode is to drive W# HIGH.

Table 3: Status Register

Bit	Name	Settings	Description	Notes
7	Status register write enable/disable	0 = Enabled (Default) 1 = Disabled	**Nonvolatile control bit:** Used with W# to enable or disable writing to the status register.	–
5	Top/bottom	0 = Top (Default) 1 = Bottom	**Nonvolatile control bit:** Determines whether the protected memory area defined by the block protect bits starts from the top or bottom of the memory array.	–
6, 4:2	BP[3:0]	See Protected Area tables	**Nonvolatile control bit:** Defines memory to be software protected against PROGRAM or ERASE operations. When one or more block protect bits is set to 1, a designated memory area is protected from PROGRAM and ERASE operations.	1
1	Write enable latch	0 = Clear (Default) 1 = Set	**Volatile control bit:** The device always powers up with this bit cleared to prevent inadvertent WRITE, PROGRAM, or ERASE operations. To enable these operations, the WRITE ENABLE operation must be executed first to set this bit.	–

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Table 3: Status Register (Continued)

Bit	Name	Settings	Description	Notes
0	Write in progress	0 = Ready (Default) 1 = Busy	**Volatile status bit:** Indicates if one of the following command cycles is in progress: WRITE STATUS REGISTER WRITE NONVOLATILE CONFIGURATION REGISTER PROGRAM ERASE	2

Notes: 1. The BULK ERASE command is executed only if all bits = 0.
      2. Status register bit 0 is the inverse of flag status register bit 7.

Block Protection Settings

Table 4: Protected Area – 128KB Sectors

Status Register Content					Protected Area	Unprotected Area
Top/Bottom	BP3	BP2	BP1	BP0		
0	0	0	0	0	None	0:511
0	0	0	0	1	511	0:510
0	0	0	1	0	510:511	0:509
0	0	0	1	1	508:511	0:507
0	0	1	0	0	504:511	0:503
0	0	1	0	1	496:511	0:495
0	0	1	1	0	480:511	0:479
0	0	1	1	1	448:511	0:447
0	1	0	0	0	384:511	0:383
0	1	0	0	1	256:511	0:255
0	1	0	1	0	0:511	None
0	1	0	1	1	0:511	None
0	1	1	0	0	0:511	None
0	1	1	0	1	0:511	None
0	1	1	1	0	0:511	None
0	1	1	1	1	0:511	None
1	0	0	0	0	None	0:511
1	0	0	0	1	0	1:511
1	0	0	1	0	0:1	2:511
1	0	0	1	1	0:3	4:511
1	0	1	0	0	0:7	8:511
1	0	1	0	1	0:15	16:511
1	0	1	1	0	0:31	32:511
1	0	1	1	1	0:63	64:511
1	1	0	0	0	0:127	128:511
1	1	0	0	1	0:255	256:511
1	1	0	1	0	0:511	None
1	1	0	1	1	0:511	None
1	1	1	0	0	0:511	None
1	1	1	0	1	0:511	None
1	1	1	1	0	0:511	None
1	1	1	1	1	0:511	None

Flag Status Register

Flag status register bits are read by using READ FLAG STATUS REGISTER command. All bits are volatile and are reset to zero on power-up.

Status bits are set and reset automatically by the internal controller. Error bits must be cleared through the CLEAR STATUS REGISTER command.

Table 5: Flag Status Register

Bit	Name	Settings	Description
7	Program or erase controller	0 = Busy 1 = Ready	**Status bit:** Indicates whether one of the following command cycles is in progress: WRITE STATUS REGISTER, WRITE NONVOLATILE CONFIGURATION REGISTER, PROGRAM, or ERASE.
6	Erase suspend	0 = Clear 1 = Suspend	**Status bit:** Indicates whether an ERASE operation has been or is going to be suspended.
5	Erase	0 = Clear 1 = Failure or protection error	**Error bit:** Indicates whether an ERASE operation has succeeded or failed.
4	Program	0 = Clear 1 = Failure or protection error	**Error bit:** Indicates whether a PROGRAM operation has succeeded or failed. It also indicates whether a CRC check has succeeded or failed.
3	Reserved	0	Reserved
2	Program suspend	0 = Clear 1 = Suspend	**Status bit:** Indicates whether a PROGRAM operation has been or is going to be suspended.
1	Protection	0 = Clear 1 = Failure or protection error	**Error bit:** Indicates whether an ERASE or PROGRAM operation has attempted to modify the protected array sector, or whether a PROGRAM operation has attempted to access the locked OTP space.
0	Addressing	0 = 3-byte addressing 1 = 4-byte addressing	**Status bit:** Indicates whether 3-byte or 4-byte address mode is enabled.

Internal Configuration Register

The memory configuration is set by an internal configuration register that is not directly accessible to users.

The user can change the default configuration at power-up by using the WRITE NONVOLATILE CONFIGURATION REGISTER. Information from the nonvolatile configuration register overwrites the internal configuration register during power-on or after a reset.

The user can change the configuration during device operation using the WRITE VOLATILE CONFIGURATION REGISTER command. Information from the volatile configuration registers overwrite the internal configuration register immediately after the WRITE command completes.

Figure 6: Internal Configuration Register
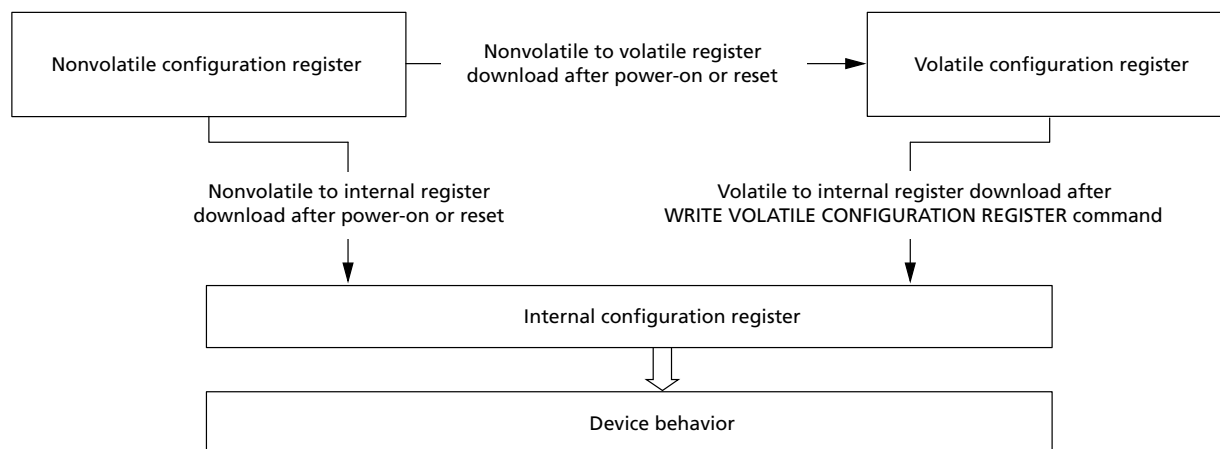
Nonvolatile Configuration Register

Nonvolatile configuration register bits set the device configuration after power-up or reset. All bits are erased (FFh) unless stated otherwise. This register is read from and written to using the READ NONVOLATILE CONFIGURATION REGISTER and the WRITE NONVOLATILE CONFIGURATION REGISTER commands, respectively. The commands use the main array address scheme, but only the LSB is used to access different register settings, thereby providing up to 256 bytes of registers (See the table below for the details). A READ command from a reserved address returns FFh. A WRITE command to a reserved setting is ignored, flag status register bit 1 is set, and the write enable latch bit is cleared.

Table 6: Nonvolatile Configuration Register

Address	Name	Settings	Description	Notes
255h:08h	Reserved	Reserved	Reserved	–
07h	Wrap configuration	FFh = Continuous (Default) FEh = 64-byte wrap FDh = 32-byte wrap FCh = 16-byte wrap Others = Reserved	Enables the device to read from memory sequentially or to wrap within 16-, 32-, or 64-byte boundaries.	–
06h	XIP configuration	FFh = XIP disabled (Default) FEh = 8IOFR XIP FDh = 8OFR XIP F8h = FAST READ XIP Others = Reserved	Enables the device to operate in the selected XIP mode immediately after power-on reset.	–
05h	Beyond 128Mb address configuration	FFh = 3-byte address (Default) FEh = 4-byte address Others = Reserved	Defines the number of address bytes for a command.	–
04h	Reserved	Reserved	Reserved	–
03h	Programmable output drive strength	FFh = 50 (Default) FEh = 35 FDh = 25 FCh = 18 Others = Reserved	Optimizes the impedance at V_{CC}/2 output voltage.	–
02h	Reserved	Reserved	Reserved	–
01h	Dummy cycle configuration	00h = Identical to 1Fh 01h = 1 dummy cycle 02h = 2 dummy cycles 03h to 1Dh = 3 to 29 dummy cycles 1Eh = 30 dummy cycles 1Fh = Default Others = Reserved	Sets the number of dummy clock cycles subsequent to all FAST READ commands (See the Command Set Table for default setting values).	1
00h	I/O mode	FFh = Extended SPI (Default) DFh = Extended SPI without DQS E7h = Octal DDR C7h = Octal DDR without DQS Others = Reserved	Sets the device to work in different I/O modes such as DDR mode or DQS mode (strobe enabled).	2

Notes: 1. The number of cycles must be set in accordance with the desired operating clock frequency and varies depending on the type of READ command/operation being used (see Supported Clock Frequencies). Insufficient dummy clock cycles for the associated operating frequency will cause the memory to output incorrect data.
2. Address 00h of the nonvolatile configuration register (NVCR) is only used for devices that come pre-configured from Micron to boot in the SDR x1 mode (I/O Pin Configuration Option 1 -- "Boot in SDR x1"). For devices pre-configured from Micron to boot in the DDR x8 mode (I/O Pin Configuration Option 2 -- "Boot in DDR x8"), the default value of this byte is FFh. In addition, for devices pre-configured to boot in the DDR x8 mode, it is not

possible for users to change address 00h of the NVCR to reconfigure devices to work in the extended SPI mode. Attempts to change address 00h will not be accepted, and the write enable latch (WEL) bit will be reset to 0 and bit 1 (the protection bit) of the flag status register (FSR) will be set to 1 to indicate a failure.

Volatile Configuration Register

Volatile configuration register bits temporarily set the device configuration after power-up or reset. All bits are erased (FFh) unless stated otherwise. This register is read from and written to using the READ VOLATILE CONFIGURATION REGISTER and the WRITE VOLATILE CONFIGURATION REGISTER commands, respectively. The commands use the main array address scheme; however, only the LSB is used to access different register settings to provide up to 256 bytes of registers (See the table below for the details). A READ command from a reserved address returns FFh. A WRITE command to a reserved setting is ignored, flag status register bit 1 is set, and the write enable latch bit is cleared. (See Supported Clock Frequencies)

Table 7: Volatile Configuration Register

Address	Name	Settings	Description	Notes
255h:08h	Reserved	Reserved	Reserved	–
07h	Wrap configuration	FFh = Continuous (Default) FEh = 64-byte wrap FDh = 32-byte wrap FCh = 16-byte wrap Others = Reserved	Enables the device to read from memory sequentially or to wrap within 16-, 32-, or 64-byte boundaries.	–
06h	XIP configuration	FFh = XIP disabled (Default) FEh = XIP enabled Others = Reserved	Enables the device to operate in the selected XIP mode. It is first required to enable XiP and then enter XIP mode using the XiP confirmation bit.	–
05h	Beyond 128Mb address configuration	FFh = 3-byte address (Default) FEh = 4-byte address Others = Reserved	Defines the number of address bytes for a command.	–
04h	Reserved	Reserved	Reserved	–
03h	Programmable output drive strength	FFh = 50 (Default) FEh = 35 FDh = 25 FCh = 18 Others = Reserved	Optimizes the impedance at $V_{CC}/2$ output voltage.	–
02h	Reserved	Reserved	Reserved	–
01h	Dummy cycle configuration	00h = Identical to 1Fh 01h = 1 dummy cycle 02h = 2 dummy cycles 03h to 1Dh = 3 to 29 dummy cycles 1Eh = 30 dummy cycles 1Fh = Default Others = Reserved	Sets the number of dummy clock cycles subsequent to all FAST READ commands (See the Command Set Table for default setting values).	1
00h	I/O mode	FFh = Extended SPI (Default) DFh = Extended SPI without DQS E7h = Octal DDR C7h = Octal DDR without DQS Others = Reserved	Sets the device to work in different I/O modes such as DDR mode or DQS mode (strobe enabled).	–

Note: 1. The number of cycles must be set to accord with the clock frequency, which varies by the type of FAST READ command (See Supported Clock Frequencies). Insufficient dummy clock cycles for the operating frequency causes the memory to read incorrect data.

Supported Clock Frequencies

Table 8: Clock Frequencies – SDR and DDR Read Starting at Any Byte Address

Note 1 applies to entire table

Number of Dummy Clock Cycles	FAST READ	Octal OUTPUT FAST READ		Octal I/O FAST READ		OCTAL DDR
	SDR	SDR	DDR	SDR	DDR	
1	100	16	NA	NA	NA	NA
2	116	33	16	NA	NA	NA
3	133	50	33	16	16	16
4	150	66	50	33	33	33
5	166	83	66	50	50	50
6	166	100	83	66	66	66
7	166	116	95	76	76	76
8	166	133	105	86	86	86
9	166	143	114	95	95	95
10	166	152	124	105	105	105
11	166	162	133	114	114	114
12	166	166	143	124	124	124
13	166	166	152	133	133	133
14	166	166	162	143	143	143
15	166	166	171	152	152	152
16	166	166	181	162	162	162
17	166	166	191	166	171	171
18	166	166	200	166	181	181
19	166	166	200	166	191	191
20 and above	166	166	200	166	200	200

Note: 1. Values are guaranteed by characterization and not 100% tested in production.

Table 9: Clock Frequencies – SDR and DDR Read 4-Byte Aligned

Note 1 applies to entire table

Number of Dummy Clock Cycles	FAST READ	Octal OUTPUT FAST READ		Octal I/O FAST READ		OCTAL DDR
	SDR	SDR	DDR	SDR	DDR	
1	100	16	NA	NA	NA	NA
2	116	33	16	NA	NA	NA
3	133	50	33	16	16	16
4	150	66	50	33	33	33
5	166	83	66	50	50	50
6	166	100	83	66	66	66
7	166	116	100	83	83	83
8	166	133	114	100	95	95
9	166	150	124	116	105	105
10	166	166	133	133	114	114
11	166	166	143	143	124	124
12	166	166	152	152	133	133
13	166	166	162	162	143	143
14	166	166	171	166	152	152
15	166	166	181	166	162	162
16	166	166	191	166	171	171
17	166	166	200	166	181	181
18	166	166	200	166	191	191
19 and above	166	166	200	166	200	200

Note: 1. Values are guaranteed by characterization and not 100% tested in production.

Table 10: Clock Frequencies – SDR and DDR Read Codeword (32-Byte) Aligned

Note 1 applies to entire table

Number of Dummy Clock Cycles	FAST READ	Octal OUTPUT FAST READ		Octal I/O FAST READ		OCTAL DDR
	SDR	SDR	DDR	SDR	DDR	
1	100	100	NA	NA	NA	NA
2	116	116	66	NA	NA	NA
3	133	133	83	50	50	50
4	150	150	100	66	66	66
5	166	166	133	100	100	100
6	166	166	150	116	116	116
7	166	166	166	133	133	133
8	166	166	183	150	150	150
9	166	166	200	166	166	166
10	166	166	200	166	183	183
11 and above	166	166	200	166	200	200

Note: 1. Values are guaranteed by characterization and not 100% tested in production.

Data Sequence Wraps by Density

Table 11: Sequence of Bytes During Wrap

Starting Address	16-Byte Wrap	32-Byte Wrap	64-Byte Wrap
0	0-1-2- . . . -15-0-1- . .	0-1-2- . . . -31-0-1- . .	0-1-2- . . . -63-0-1- . .
1	1-2- . . . -15-0-1-2- . .	1-2- . . . -31-0-1-2- . .	1-2- . . . -63-0-1-2- . .
....	....	....	....
15	15-0-1-2-3- . . . -15-0-1- . .	15-16-17- . . . -31-0-1- . .	15-16-17- . . . -63-0-1- . .
:	:	:	:
31	–	31-0-1-2-3- . . . -31-0-1- . .	31-32-33- . . . -63-0-1- . .
:	:	:	:
63	–	–	63-0-1- . . . -63-0-1- . .

Security Registers

Security registers enable sector and password protection on multiple levels using nonvolatile and volatile register and bit settings (shown below). The applicable register tables follow.

Figure 7: Sector and Password Protection
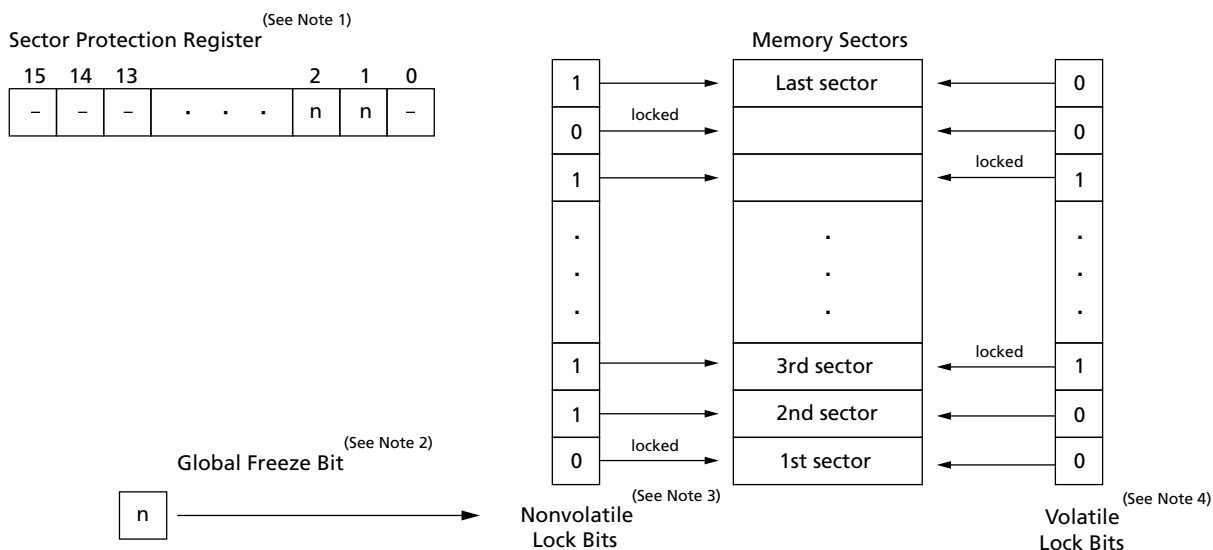
Notes:
1. **Sector protection register.** This 16-bit nonvolatile register includes two active bits[2:1] to enable sector and password protection.
2. **Global freeze bit.** This volatile bit protects the settings in all nonvolatile lock bits.
3. **Nonvolatile lock bits.** Each nonvolatile bit corresponds to and provides nonvolatile protection for an individual memory sector, which remains locked (protection enabled) until its corresponding bit is cleared to 1.
4. **Volatile lock bits.** Each volatile bit corresponds to and provides volatile protection for an individual memory sector, which is locked temporarily (protection is cleared when the device is reset or powered down).

Sector Protection Security Register

Table 12: Sector Protection Register

Bits	Name	Settings	Description	Notes
15:3	Reserved	1 = Default	–	–
2	Password protection lock	1 = Disabled (default) 0 = Enabled	**Nonvolatile bit:** When set to 1, password protection is disabled. When set to 0, password protection is enabled permanently; the 64-bit password cannot be retrieved or reset.	1, 2
1	Sector protection lock	1 = Enabled, with password protection (default) 0 = Enabled, without password protection	**Nonvolatile bit:** When set to 1, nonvolatile lock bits can be set to lock/unlock their corresponding memory sectors; bit 2 can be set to 0, enabling password protection permanently. When set to 0, nonvolatile lock bits can be set to lock/unlock their corresponding memory sectors; bit 2 must remain set to 1, disabling password protection permanently.	1, 3, 4
0	Reserved	1 = Default	–	–

Notes: 1. Bits 2 and 1 are user-configurable, one-time-programmable, and mutually exclusive in that only one of them can be set to 0. It is recommended that one of the bits be set to 0 when first programming the device.

2. The 64-bit password must be programmed and verified before this bit is set to 0 because after it is set, password changes are not allowed, thus providing protection from malicious software. When this bit is set to 0, a 64-bit password is required to reset the global freeze bit from 0 to 1. In addition, if the password is incorrect or lost, the global freeze bit can no longer be set and nonvolatile lock bits cannot be changed. (See the Sector and Password Protection figure and the Global Freeze Bit Definition table).

3. Whether this bit is set to 1 or 0, it enables programming or erasing nonvolatile lock bits (which provide memory sector protection). The password protection bit must be set beforehand because setting this bit will either enable password protection permanently (bit 2 = 0) or disable password protection permanently (bit 1 = 0).

4. By default, all sectors are unlocked when the device is shipped from the factory. Sectors are locked, unlocked, read, or locked down as explained in the Nonvolatile and Volatile Lock Bits table and the Volatile Lock Bit Register Bit Definitions table.

Table 13: Global Freeze Bit

Bits	Name	Settings	Description
7:1	Reserved	0	Bit values are 0
0	Global freeze bit	1 = Disabled (default) 0 = Enabled	**Volatile bit:** When set to 1, all nonvolatile lock bits can be set to enable or disable locking their corresponding memory sectors. When set to 0, nonvolatile lock bits are protected from PROGRAM or ERASE commands. This bit should not be set to 0 until the nonvolatile lock bits are set.

Note: 1. The READ GLOBAL FREEZE BIT command enables reading this bit. When password protection is enabled, this bit is locked upon device power-up or reset. It cannot be changed without the password. After the password is entered, the UNLOCK PASSWORD command resets this bit to 1, enabling programing or erasing the nonvolatile lock bits. After the bits are changed, the WRITE GLOBAL FREEZE BIT command sets this bit to 0, protecting the nonvolatile lock bits from PROGRAM or ERASE operations.

Nonvolatile and Volatile Sector Lock Bits Security

Table 14: Nonvolatile and Volatile Lock Bits

Bit Details	Nonvolatile Lock Bit	Volatile Lock Bit
Description	Each sector of memory has one corresponding nonvolatile lock bit	Each sector of memory has one corresponding volatile lock bit; this bit is the sector write lock bit described in the Volatile Lock Bit Register table.
Function	When set to 0, locks and protects its corresponding memory sector from PROGRAM or ERASE operations. Because this bit is nonvolatile, the sector remains locked, protection enabled, until the bit is cleared to 1.	When set to 1, locks and protects its corresponding memory sector from PROGRAM or ERASE operations. Because this bit is volatile, protection is temporary. The sector is unlocked, protection disabled, upon device reset or power-down.
Settings	1 = Lock disabled 0 = Lock enabled	0 = Lock disabled 1 = Lock enabled
Enabling protection	The bit is set to 0 by the WRITE NONVOLATILE LOCK BITS command, enabling protection for designated locked sectors. Programming a sector lock bit requires the typical byte programming time.	The bit is set to 1 by the WRITE VOLATILE LOCK BITS command, enabling protection for designated locked sectors.
Disabling protection	All bits are cleared to 1 by the ERASE NONVOLATILE LOCK BITS command, unlocking and disabling protection for all sectors simultaneously. Erasing all sector lock bits requires typical sector erase time.	All bits are set to 0 upon reset or power-down, unlocking and disabling protection for all sectors.
Reading the bit	Bits are read by the READ NONVOLATILE LOCK BITS command.	Bits are read by the READ VOLATILE LOCK BITS command.

Nonvolatile Lock Bit Security Register

For nonvolatile sector locking, the nonvolatile lock bits are stored in flash cells within an erasable sector lock-bit array, hence, making this a nonvolatile locking scheme. An erased flash cell corresponds to an unlocked sector and a programmed flash cell corresponds to a locked sector.

One of nonvolatile lock bits is related to each sector, the nonvolatile lock bits are programmed individually but must be erased as a group.

Programming nonvolatile lock bits requires the typical byte programming time. Erasing all the nonvolatile lock bits requires typical sector erase time.

Table 15: Nonvolatile Lock Bit Register

Nonvolatile Lock Bit Value	Protection Status
00h	Sector protected from modify operations
FFh	Sector unprotected from modify operations (default).

Volatile Lock Bit Security Register

One volatile lock bit register is associated with each sector of memory. It enables the sector to be locked, unlocked, or locked-down with the WRITE VOLATILE LOCK BITS command, which executes only when sector lock down (bit 1) is set to 0. Each register can be read with the READ VOLATILE LOCK BITS command. This register is compatible with and provides the same locking capability as the lock register in the Micron N25Q SPI NOR family.

Table 16: Volatile Lock Bit Register

Bit	Name	Settings	Description
7:2	Reserved	0	Bit values are 0.
1	Sector lock down	0 = Lock-down disabled (default) 1 = Lock-down enabled	**Volatile bit:** Device always powers up with this bit set to 0 so that sector lock down and sector write lock bits can be set to 1. When this bit set to 1, neither of the two volatile lock bits can be written to until the next power cycle, hardware, or software reset.
0	Sector write lock	0 = Write lock disabled (default) 1 = Write lock enabled	**Volatile bit:** Device always powers up with this bit set to 0 so that PROGRAM and ERASE operations in this sector can be executed and sector content modified. When this bit is set to 1, PROGRAM and ERASE operations in this sector are not executed.

Protection Management Register

Protection management register settings enable or disable enhanced security features for the device. Protection management register bits can be read from or written to using the READ PROTECTION MANAGEMENT REGISTER and WRITE PROTECTION MANAGEMENT REGISTER commands.

When the protection management register lockdown bit (bit 2) is set to 0, the device does not respond to WRITE PROTECTION MANAGEMENT REGISTER commands. Commands are ignored, the register remains unchanged, and an error code is set in flag status register bits 1 and 4.

Note: When enhanced security features are not going to be used, programming protection management register bit 2 to a value of 0 is strongly recommended. This prevents unintentional or malicious operations on the register that could result in permanent and irreversible locking of the memory sectors.

Table 17: Protection Management Register

Bit	Name	Settings	Description
7	Reserved	Reserved	Reserved
6	Reserved	Reserved	Reserved
5	Data protection at power up	0 = Lock 1 = Unlock (default)	**OTP control bit:** Sets all sector lock bits. This prevents potential data corruption from errant commands sent to the memory. Sector lock bits remain set from the time external power is available.
4	Status Register Lock	0 = Lock 1 = Unlock (default)	**OTP control bit:** Permanently locks the status register. This prevents further writes to the status register, regardless of the state of the W# pin and the write enable/disable bit of the status register.
3	Reserved	Reserved	Reserved
2	PMR lockdown	0 = Lock 1 = Unlock (default)	**OTP control bit:** Permanently locks the protection management register.
1	Nonvolatile sector lock bit register lockdown	0 = Lock 1 = Unlock (default)	**OTP control:** Permanently locks contents of the nonvolatile sector lock bit register. When this bit is set to 0, the nonvolatile lock bits are locked from PROGRAM and ERASE operations. Nonvolatile lock bits cannot be unlocked.
0	Nonvolatile sector lock bit erase lock	0 = Lock 1 = Unlock (default)	**OTP control:** When this bit is set to 1, the nonvolatile sector lock bit register array is erasable; otherwise, it is unerasable.

Protection Management Register Operations

Protection management register bits can be read with the READ PROTECTION MANAGEMENT REGISTER (2Bh) command. They can be programmed independently or collectively with the WRITE PROTECTION MANAGEMENT REGISTER command (68h). The bits are one-time programmable and cannot be erased.

To initiate a READ PROTECTION MANAGEMENT REGISTER command, S# is driven LOW. For extended SPI protocol, input is on DQ0, output on DQ1. For dual SPI protocol, input/output is on DQ[1:0]. For Octal DDR protocol, input/output is on DQ[7:0]. The operation is terminated by driving S# HIGH at any time during data output.

Before a WRITE PROTECTION MANAGEMENT REGISTER command is initiated, the WRITE ENABLE command must be executed to set the write enable latch bit to 1. To initiate a command, S# is driven LOW and held LOW until the eighth bit of the last data byte has been latched in, after which it must be driven HIGH. For the extended SPI and Octal DDR protocols, input is on DQ0, and DQ[7:0], respectively, followed by the data bytes. . If S# is not driven HIGH, the command is not executed, error bits are not set, and the write enable latch remains set to 1. The operation is self-timed and its duration is ^{t}PPMR.

Table 18: Protection Management Register Operations

Operation Name	Description/Conditions
READ PROTECTION MANAGEMENT REGISTER (2Bh)	The command does not require dummy cycles in extended SPI protocol, while 8 dummy cycles are necessary in Octal DDR protocol. When the register is read continuously, the same byte is output repeatedly.
WRITE PROTECTION MANAGEMENT REGISTER (68h)	When an operation is in progress, the write in progress bit is set to 1. The write enable latch bit is cleared to 0, whether the operation is successful or not. The status register and flag status register can be polled for the operation status. When the operation completes, the write in progress bit is cleared to 0, whether the operation is successful or not. For stacked devices (1Gb and 2Gb) it is possible to obtain the operation status by reading the flag status register a number of times corresponding to the die stacked, with S# toggled in between the READ FLAG STATUS REGISTER commands. When the operation completes, the program or erase controller bit of the flag status register is cleared to 1. The end of operation can be detected when the program or erase controller bit of the flag status register outputs 1 for all the die of the stack. When a 0 is written to any reserved field, the operation is initiated; however, uCode aborts the operation without programming any bits. Then the write enable latch bit is cleared, and the program error bit and protection error bits are set to 1. When protection management bit 2 is set to 0 (locked), the command is not executed, the write enable latch remains set to 1, and flag status register and protection error bits are set to 1.

Device ID Data

The device ID data shown in the tables here is read by the READ ID and MULTIPLE I/O READ ID operations.

Table 19: Device ID Data

Byte#	Name	Content Value	Assigned By
Manufacturer ID (1 Byte total)			

Table 19: Device ID Data (Continued)

Byte#	Name	Content Value		Assigned By
1	Manufacturer ID (1 Byte)	2Ch		JEDEC
Device ID (2 bytes total)				
2	Memory type (1 Byte)	5Ah = 3V		Manufacturer
		5Bh = 1.8V		
3	Memory capacity (1 byte)	1Ch = 2Gb		
		1Bh = 1Gb		
		1Ah = 512Mb		
		19h = 256Mb		
Unique ID (17 bytes total)				
4	Indicates the number of remaining ID bytes (1 byte)	10h		Factory
5	Extended device ID (1 byte)	See Extended Device ID table		
6	Device configuration information (1 byte)	See Device Configuration Information table		
7:20	Customized factory data (14 bytes)	Unique ID code (UID)		

Table 20: Extended Device ID Data, First Byte

Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
Reserved	Device generation 1 = 2nd generation	Reserved	Reserved	Reserved	Reserved	Sector size: 01 = Uniform 128KB	

Table 21: Device Configuration Information Data

Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
Reserved	Reserved	Reserved	Reserved	Reserved	Boot up protocol: 0 = Boot in SDR ×1 1 = Boot in DDR ×8	Reserved	

Serial Flash Discovery Parameter Data

The serial flash discovery parameter (SFDP) provides a standard, consistent method to describe serial flash device functions and features using internal parameter tables. The parameter tables can be interrogated by host system software, enabling adjustments to accommodate divergent features from multiple vendors. The SFDP standard defines a common parameter table that describes important device characteristics and serial access methods used to read the parameter table data. The Micron SFDP table information aligns with JEDEC-standard JESD216 for serial flash discoverable parameters. Data in the SFDP tables is read by the READ SERIAL FLASH DISCOVERY PARAMETER operation. See Micron TN-12-35: Serial Flash Discovery Parameters for MT35X Family for serial flash discovery parameter data.

Command Definitions

Table 22: Command Set

Command	Code	Extended SPI		Octal SPI		Address Bytes	Data Bytes
		Command-Address-Data	Dummy Clock Cycles	Command-Address-Data	Dummy Clock Cycles		
Software RESET Operations							
RESET ENABLE	66h	1-0-0	0	8-0-0	0	0	0
RESET MEMORY	99h	1-0-0	0	8-0-0	0	0	0
READ ID Operations							
READ ID	9E/9Fh	1-0-1	0	8-0-8	8	0	1 to 20
READ SERIAL FLASH DISCOVERY PARAMETER	5Ah	1-1-1	8	8-8-8	8	3[1]	1 to ∞
READ MEMORY Operations							
READ	03h	1-1-1	0	–	–	3[2]	1 to ∞
FAST READ	0Bh	1-1-1	8	8-8-8	16	3[2]	1 to ∞
OCTAL OUTPUT FAST READ	8Bh	1-1-8	8	8-8-8	16	3[2]	1 to ∞
OCTAL I/O FAST READ	CBh	1-8-8	16	8-8-8	16	3[2]	1 to ∞
DDR OCTAL OUTPUT FAST READ	9Dh	1-1-8	8	8-8-8	16	3[2]	1 to ∞
DDR OCTAL I/O FAST READ	FDh	1-8-8	16	8-8-8	16	4	1 to ∞
READ MEMORY Operations with 4-Byte Address							
4-BYTE READ	13h	1-1-1	0	–	–	4	1 to ∞
4-BYTE FAST READ	0Ch	1-1-1	8	8-8-8	16	4	1 to ∞
4-BYTE OCTAL OUTPUT FAST READ	7Ch	1-1-8	8	8-8-8	16	4	1 to ∞
4-BYTE OCTAL I/O FAST READ	CCh	1-8-8	16	8-8-8	16	4	1 to ∞
WRITE Operations							
WRITE ENABLE	06h	1-0-0	0	8-0-0	0	0	0
WRITE DISABLE	04h	1-0-0	0	8-0-0	0	0	0
READ REGISTER Operations							
READ STATUS REGISTER	05h	1-0-1	0	8-0-8	8	0	1 to ∞
READ FLAG STATUS REGISTER	70h	1-0-1	0	8-0-8	8	0	1 to ∞
READ NONVOLATILE CONFIGURATION REGISTER	B5h	1-1-1	8	8-8-8	8	3[2]	1 to ∞
READ VOLATILE CONFIGURATION REGISTER	85h	1-1-1	8	8-8-8	8	3[2]	1 to ∞
READ PROTECTION MANAGEMENT REGISTER	2Bh	1-0-1	0	8-0-8	8	0	1 to ∞
READ GENERAL PURPOSE READ REGISTER	96h[3, 4]	1-0-1	8	8-0-8	8	0	1 to ∞
WRITE REGISTER Operations							
WRITE STATUS REGISTER	01h	1-0-1	0	8-0-8	0	0	1

Table 22: Command Set (Continued)

Command	Code	Extended SPI		Octal SPI		Address Bytes	Data Bytes
		Command-Address-Data	Dummy Clock Cycles	Command-Address-Data	Dummy Clock Cycles		
WRITE NONVOLATILE CONFIGURATION REGISTER	B1h	1-1-1	0	8-8-8	0	3^2	1
WRITE VOLATILE CONFIGURATION REGISTER	81h	1-1-1	0	8-8-8	0	3^2	1
WRITE PROTECTION MANAGEMENT REGISTER	68h	1-0-1	0	8-0-8	0	0	1
CLEAR FLAG STATUS REGISTER Operation							
CLEAR FLAG STATUS REGISTER	50h	1-0-0	0	8-0-0	0	0	0
PROGRAM Operations							
PAGE PROGRAM	02h	1-1-1	0	8-8-8	0	3^2	1 to 256
OCTAL INPUT FAST PROGRAM	82h	1-1-8	0	8-8-8	0	3^2	1 to 256
EXTENDED OCTAL INPUT FAST PROGRAM	C2h	1-8-8	0	8-8-8	0	3^2	1 to 256
PROGRAM Operations with 4-Byte Address							
4-BYTE PAGE PROGRAM	12h	1-1-1	0	8-8-8	0	4	1 to 256
4-BYTE OCTAL INPUT FAST PROGRAM	84h	1-1-8	0	8-8-8	0	4	1 to 256
4-BYTE OCTAL INPUT EXTENDED FAST PROGRAM	8Eh	1-8-8	0	8-8-8	0	4	1 to 256
ERASE Operations							
32KB SUBSECTOR ERASE	52h	1-1-0	0	8-8-0	0	3^2	0
4KB SUBSECTOR ERASE	20h	1-1-0	0	8-8-0	0	3^2	0
SECTOR ERASE	D8h	1-1-0	0	8-8-0	0	3^2	0
BULK ERASE	C7h/60h	1-0-0	0	8-0-0	0	0	0
ERASE Operations with 4-Byte Address							
4-BYTE SECTOR ERASE	DCh	1-1-0	0	8-8-0	0	4	0
4-BYTE 4KB SUBSECTOR ERASE	21h	1-1-0	0	8-8-0	0	4	0
4-BYTE 32KB SUBSECTOR ERASE	5Ch	1-1-0	0	8-8-0	0	4	0
SUSPEND/RESUME Operations							
PROGRAM/ERASE SUSPEND	75h	1-0-0	0	8-0-0	0	0	0
PROGRAM/ERASE RESUME	7Ah	1-0-0	0	8-0-0	0	0	0
ONE-TIME PROGRAMMABLE (OTP) Operations							
READ OTP ARRAY	4Bh	1-1-1	8	8-8-8	16	3^2	1 to 65
PROGRAM OTP ARRAY	42h	1-1-1	0	8-8-8	0	3^2	1 to 65
4-BYTE ADDRESS MODE Operations							
ENTER 4-BYTE ADDRESS MODE	B7h	1-0-0	0	8-0-0	0	0	0
EXIT 4-BYTE ADDRESS MODE	E9h	1-0-0	0	8-0-0	0	0	0
DEEP POWER-DOWN Operations							

Table 22: Command Set (Continued)

Command	Code	Extended SPI Command-Address-Data	Extended SPI Dummy Clock Cycles	Octal SPI Command-Address-Data	Octal SPI Dummy Clock Cycles	Address Bytes	Data Bytes
ENTER DEEP POWER-DOWN	B9h	1-0-0	0	8-0-0	0	0	0
RELEASE FROM DEEP POWER-DOWN	ABh	1-0-0	0	8-0-0	0	0	0
ADVANCED SECTOR PROTECTION Operations							
READ SECTOR PROTECTION	2Dh	1-0-1	0	8-0-8	8	0	1 to ∞
PROGRAM SECTOR PROTECTION	2Ch	1-0-1	0	8-0-8	0	0	2
READ VOLATILE LOCK BITS	E8h	1-1-1	0	8-8-8	8	3^2	1 to ∞
WRITE VOLATILE LOCK BITS	E5h	1-1-1	0	8-8-8	0	3^2	1
READ NONVOLATILE LOCK BITS	E2h	1-1-1	0	8-8-8	8	4	1 to ∞
WRITE NONVOLATILE LOCK BITS	E3h	1-1-0	0	8-8-0	0	4	0
ERASE NONVOLATILE LOCK BITS	E4h	1-0-0	0	8-0-0	0	0	0
READ GLOBAL FREEZE BIT	A7h	1-0-1	0	8-0-8	8	0	1 to ∞
WRITE GLOBAL FREEZE BIT	A6h	1-0-0	0	8-0-0	0	0	0
READ PASSWORD	27h[5]	1-0-1	0	8-0-8	8	0	1 to ∞
WRITE PASSWORD	28h	1-0-1	0	8-0-8	0	0	8
UNLOCK PASSWORD	29h	1-0-1	0	8-0-8	0	0	8
ADVANCED SECTOR PROTECTION Operations with 4-Byte Address							
4-BYTE READ VOLATILE LOCK BITS	E0h	1-1-1	0	8-8-8	8	4	1 to ∞
4-BYTE WRITE VOLATILE LOCK BITS	E1h	1-1-1	0	8-8-8	0	4	1
ADVANCED FUNCTION INTERFACE Operations							
CYCLIC REDUNDANCY CHECK	9Bh/27h	1-0-1	0	8-0-8	0	0	10 or 18

Notes: 1. Read SFDP instruction accepts only 3-byte address even if the device is configured to 4-byte address mode. In octal DDR mode, it will be fixed 4-byte address cycle. The number of dummy cycles for the READ SFDP command is fixed (8 dummy cycles) and is not affected by dummy cycle settings in the nonvolatile configuration register and volatile configuration register. For the max clock frequency achievable refer to Supported Clock Frequencies tables for 8 dummy cycles.

2. Requires 4 bytes of address if the device is configured to 4-byte address mode or octal DDR protocol.

3. The number of dummy cycles for the READ GENERAL PURPOSE READ REGISTER command is fixed (8 dummy cycles) and is not affected by dummy cycle settings in the nonvolatile configuration register and volatile configuration register.

4. The general purpose read register is 64 bytes. After the first 64 bytes, the device outputs wrap.

5. After the 8-bit instruction shifted in, the 64-bit data are shifted out, the least significant byte first, most significant bit of each byte first. The READ PASSWORD instruction is terminated by driving chip select (S#) HIGH at any time during data output. When read continuously, the device outputs the 64-bit data repeatedly.
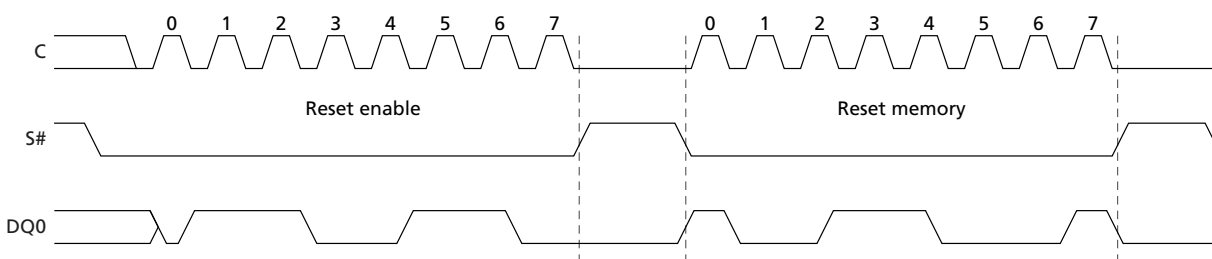
Software RESET Operations

RESET ENABLE and RESET MEMORY Commands

To initiate these commands, S# is driven LOW and the command code is input on DQ0. A minimum deselection time of ^{t}SHSL2 must come between RESET ENABLE and RESET MEMORY or reset is not guaranteed. Then, S# must be driven HIGH for the device to enter power-on reset. A time of ^{t}SHSL3 is required before the device can be reselected by driving S# LOW.

Table 23: RESET ENABLE and RESET MEMORY Operations

Operation Name	Description/Conditions
RESET ENABLE (66h)	To reset the device, the RESET ENABLE command must be followed by the RESET MEMORY command. When the two commands are executed, the device enters a power-on reset condition. It is recommended to exit XIP mode before executing these two commands.
RESET MEMORY (99h)	All volatile lock bits and the volatile configuration register are reset to the power-on reset default condition according to nonvolatile configuration register settings. If a reset is initiated while a WRITE, PROGRAM, or ERASE operation is in progress or suspended, the operation is aborted and data may be corrupted. Reset is effective after the flag status register bit 7 outputs 1 with at least one byte output. A RESET ENABLE command is not accepted during WRITE STATUS REGISTER and WRITE NONVOLATILE CONFIGURATION REGISTER operations.

Figure 8: RESET ENABLE and RESET MEMORY – 66h and 99h

Note: 1. The octal DDR protocol uses eight data pins to transmit information.

READ ID Operation

READ ID Command

To initiate this command, S# is driven LOW and the command code is input on DQ*n*. When S# is driven HIGH, the device goes to standby. The operation is terminated by driving S# HIGH at any time during data output.

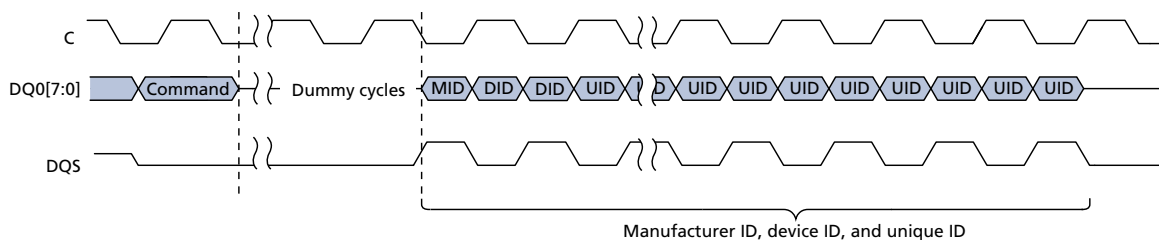**Table 24: READ ID Operation**

Operation Name	Description/Conditions
READ ID (9Eh/9Fh)	Outputs information shown in the Device ID Data tables. If an ERASE or PROGRAM cycle is in progress when the command is initiated, the command is not decoded and the command cycle in progress is not affected.

Figure 9: READ ID Command
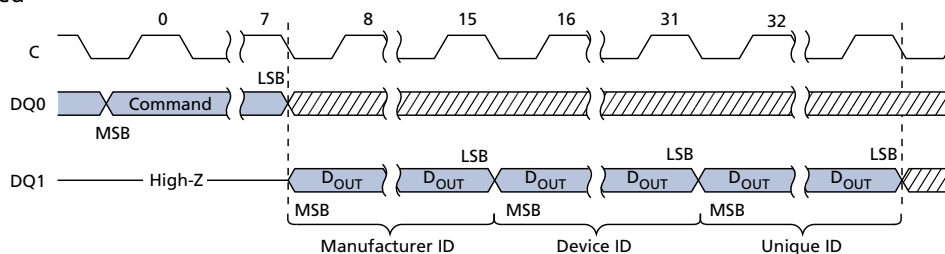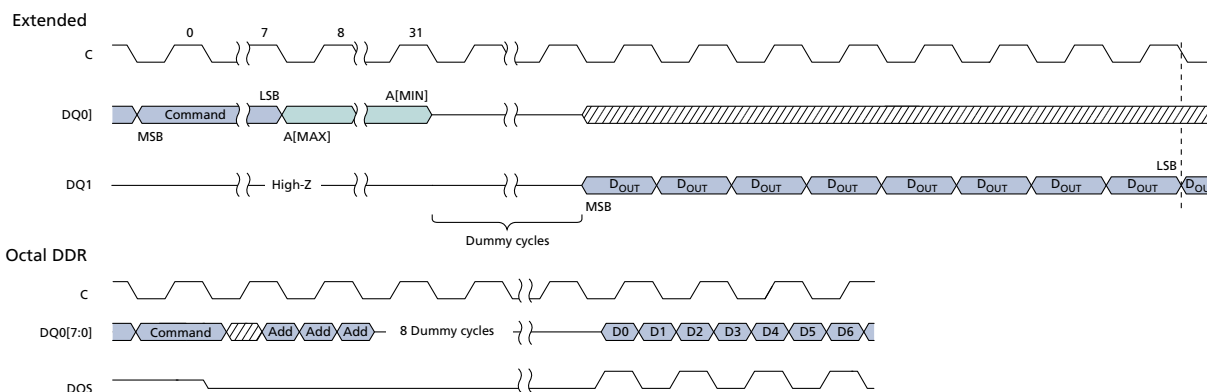

Note: 1. S# not shown.

READ SERIAL FLASH DISCOVERY PARAMETER Operation

READ SERIAL FLASH DISCOVERY PARAMETER Command

To execute READ SERIAL FLASH DISCOVERY PARAMETER command, S# is driven LOW. The command code is input on DQ0, followed by three address bytes and eight dummy clock cycles. The device outputs the information starting from the specified address. When the 2048-byte boundary is reached, the data output wraps to address 0 of the Serial Flash Discovery Parameter Data table. The operation is terminated by driving S# HIGH at any time during data output.

Note: The operation always executes in continuous mode so the read burst wrap setting in the volatile configuration register does not apply.

Figure 10: READ SERIAL FLASH DISCOVERY PARAMETER Command – 5Ah

Note: 1. S# not shown.

READ MEMORY Operations

To initiate a command, S# is driven LOW and the command code is input on DQ*n*, followed by input of the address bytes on DQ*n*. The operation is terminated by driving S# HIGH at any time during data output.

Table 25: READ MEMORY Operations

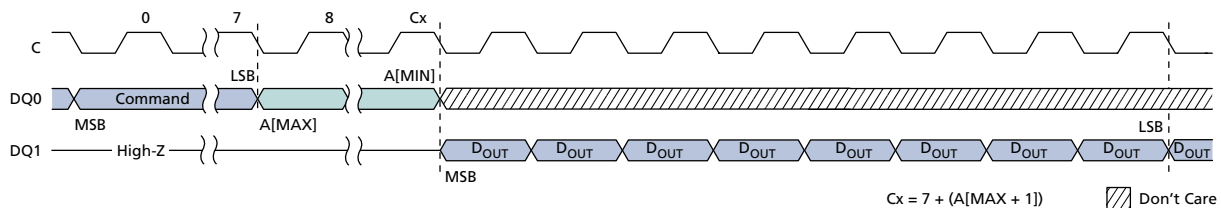| Operation Name	Description/Conditions
READ (03h)	The device supports 3-bytes addressing (default), with A[23:0] input during address cycle. After any READ command is executed, the device will output data from the selected address. After the boundary is reached, the device will start reading again from the beginning.
FAST READ (0Bh)	
OCTAL OUTPUT FAST READ (8Bh)	
OCTAL I/O FAST READ (CBh)	Each address bit is latched in during the rising edge of the clock. The addressed byte can be at any location, and the address automatically increments to the next address after each byte of data is shifted out; therefore, a die can be read with a single command.
DDR OCTAL OUTPUT FAST READ (9Dh)	FAST READ can operate at a higher frequency (^fC).
DDR OCTAL I/O FAST READ (FDh)	DDR commands function in DDR protocol regardless of settings in the nonvolatile configuration register; other commands function in DDR protocol only after DDR protocol is enabled by the register settings. Due to the nature of DDR protocol, an even number of bytes is always transferred. The least significant bit of the byte address shall always be zero when using the DDR protocol. Please note that if the least significant bit of the address is set to one when using the DDR protocol, the results are indeterminate.

4-BYTE READ MEMORY Operations

Table 26: 4-BYTE READ MEMORY Operations

Operation Name	Description/Conditions
4-BYTE READ (13h)	READ MEMORY operations can be extended to a 4-bytes address range, with [A31:0] input during address cycle.
4-BYTE FAST READ (0Ch)	Selection of the 3-byte or 4-byte address range can be enabled in two ways: through the nonvolatile configuration register or through the ENABLE 4-BYTE ADDRESS MODE/EXIT 4-BYTE ADDRESS MODE commands.
4-BYTE OCTAL OUTPUT FAST READ (7Ch)	
4-BYTE OCTAL I/O FAST READ (CCh)	Each address bit is latched in during the rising edge of the clock. The addressed byte can be at any location, and the address automatically increments to the next address after each byte of data is shifted out; therefore, a die can be read with a single command. FAST READ can operate at a higher frequency (^fC).

READ MEMORY Operations Timings

Figure 11: READ – 03h/13h[2]

Notes: 1. S# not shown.
    2. READ and 4-BYTE READ commands.

Figure 12: FAST READ – 0Bh/0Ch[3]
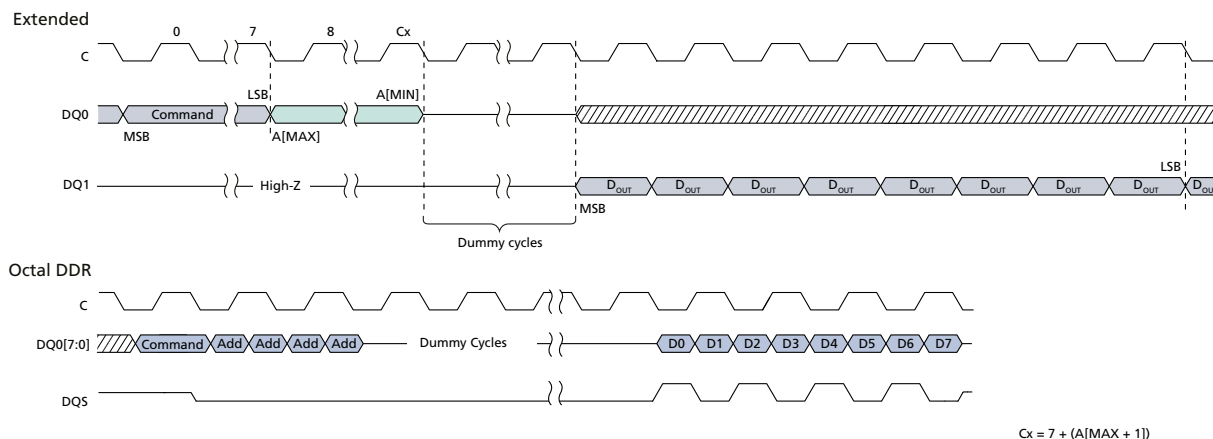
Notes: 1. Timing shows command code 0Bh but this timing also applies to the following DDR protocol command codes, for which device behavior is identical: 8Bh, CBh, 9D, FD, 7C, and CC.
    2. S# not shown.
    3. FAST READ and 4-BYTE FAST READ commands.

Figure 13: OCTAL OUTPUT FAST READ – 8Bh/7Ch[3]
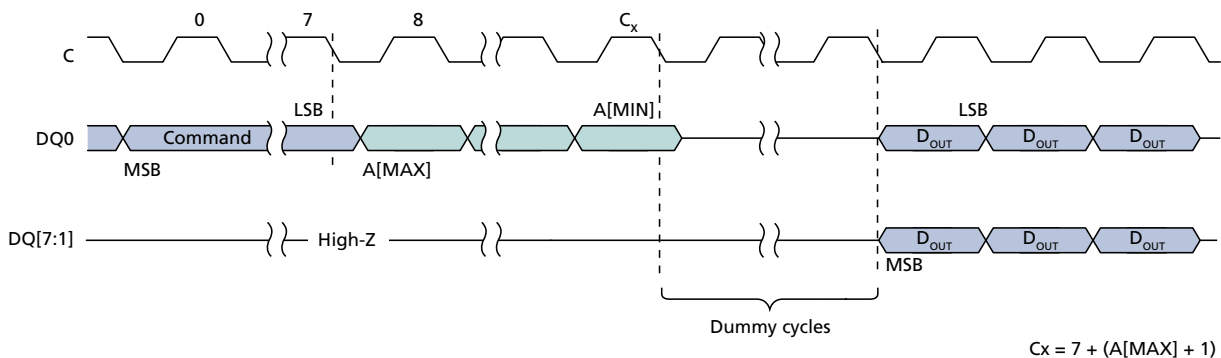
Notes: 1. Requires 32-bit address in 4-byte address configuration. In octal DDR protocol, the command, address, and data-out bits are transmitted on all eight data pins in DDR mode. The address is fixed with 4-byte.
    2. S# not shown.
    3. FAST READ and 4-BYTE FAST READ commands.

Figure 14: OCTAL I/O FAST READ – CBh/CCh[3]
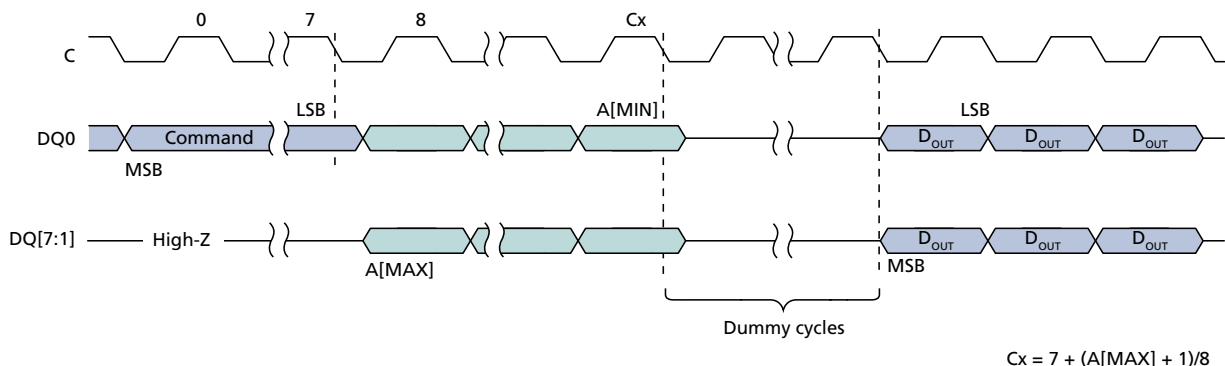
C

DQ0 Command ... LSB / MSB ... A[MIN] ... LSB D_{OUT} D_{OUT} D_{OUT}

DQ[7:1] High-Z ... A[MAX] ... D_{OUT} D_{OUT} D_{OUT} MSB

Dummy cycles

$$Cx = 7 + (A[MAX] + 1)/8$$

Notes: 1. Requires 32-bit address in 4-byte address configuration. In octal DDR protocol, the command, address, and data-out bits are transmitted on all eight data pins in DDR mode. The address is fixed with 4-byte.
   2. S# not shown.
   3. FAST READ and 4-BYTE FAST READ commands.

Figure 15: OCTAL OUTPUT FAST READ with DDR ADDRESS and DATA – 9Dh

C

DQ0 Command ... LSB / MSB ... A[MAX] ... A[MIN] ... LSB $D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$

DQ[7:1] High-Z ... $D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$ MSB
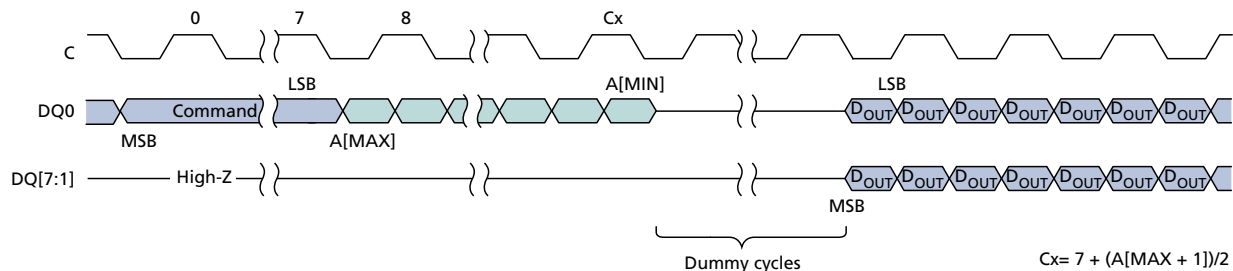
Dummy cycles

$$Cx = 7 + (A[MAX + 1])/2$$

Notes: 1. Requires 32-bit address in 4-byte address configuration. In octal DDR protocol, the command, address, and data-out bits are transmitted on all eight data pins in DDR mode. The address is fixed with 4-byte.
   2. S# not shown.

Figure 16: OCTAL I/O FAST READ with DDR ADDRESS and DATA – FDh

C

DQ0 Command ... LSB / MSB ... A[MIN] ... LSB $D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$

DQ[7:1] High-Z ... A[MAX] ... $D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$$D_{OUT}$ MSB
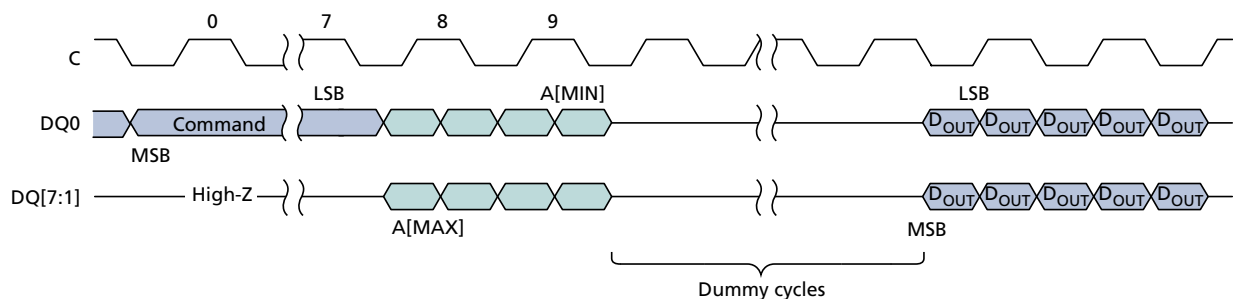
Dummy cycles

Notes: 1. Requires 32-bit address in 4-byte address configuration. In octal DDR protocol, the command, address, and data-out bits are transmitted on all eight data pins in DDR mode. The address is fixed with 4-byte.
   2. S# not shown.

WRITE ENABLE/DISABLE Operations

To initiate a command, S# is driven LOW and held LOW until the eighth bit of the command code has been latched in, after which it must be driven HIGH. For extended and octal SPI protocols respectively, the command code is input on DQ0 and DQ[7:0], respectively. If S# is not driven HIGH after the command code has been latched in, the command is not executed, flag status register error bits are not set, and the write enable latch remains cleared to its default setting of 0, providing protection against errant data modification.

Table 27: WRITE ENABLE/DISABLE Operations

Operation Name	Description/Conditions
WRITE ENABLE (06h)	Sets the write enable latch bit before each PROGRAM, ERASE, and WRITE command.
WRITE DISABLE (04h)	Clears the write enable latch bit. In case of a protection error, WRITE DISABLE will not clear the bit. Instead, a CLEAR FLAG STATUS REGISTER command must be issued to clear both flags.

Figure 17: WRITE ENABLE and WRITE DISABLE Timing
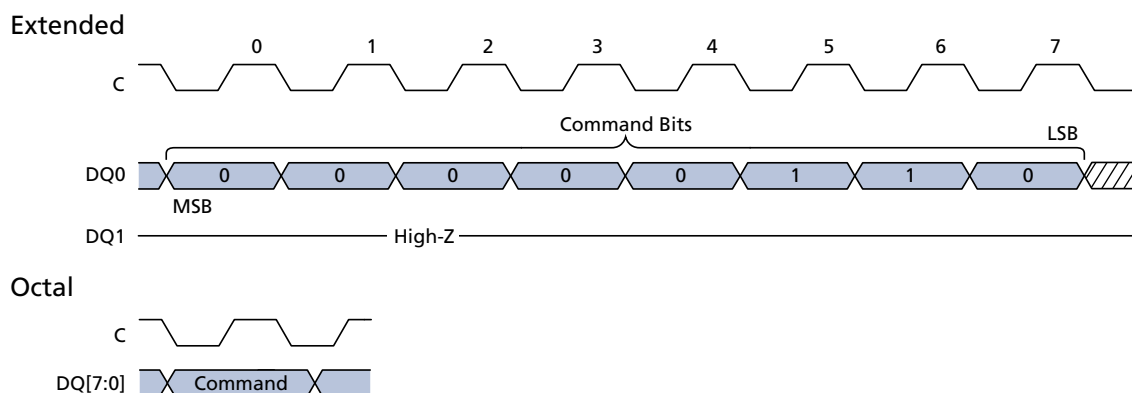
Note: 1. WRITE ENABLE command sequence and code, shown here, is 06h (0000 0110 binary); WRITE DISABLE is identical, but its command code is 04h (0000 0100 binary).

READ REGISTER Operations

To initiate a command, S# is driven LOW. For extended SPI protocol, input is on DQ0, output on DQ1. For octal SPI protocol, I/O is on DQ[7:0]. The operation is terminated by driving S# HIGH at any time during data output.

Table 28: READ REGISTER Operations

Operation Name	Description/Conditions
READ STATUS REGISTER (05h)	Can be read continuously and at any time, including during a PROGRAM, ERASE, or WRITE operation. If one of these operations is in progress, checking the write in progress bit or P/E controller bit is recommended before executing the command.
READ FLAG STATUS REGISTER (70h)	
READ NONVOLATILE CONFIGURATION REGISTER (B5h)	When continuously read, the device outputs the same byte repeatedly. All reserved fields output a value of 1.
READ VOLATILE CONFIGURATION REGISTER (85h)	When continuously read, the device outputs the same byte repeatedly. All reserved fields output a value of 1.

Figure 18: READ STATUS REGISTER – 05h
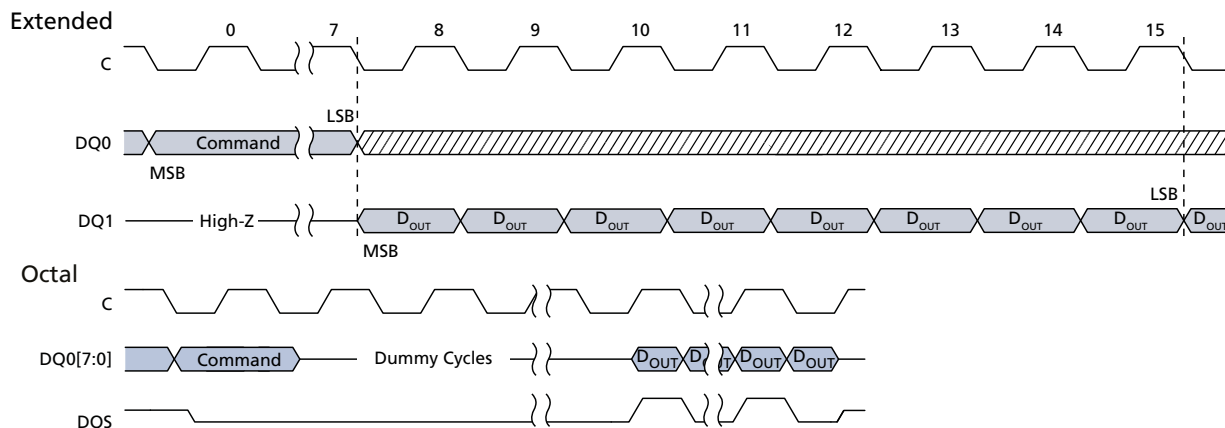
Figure 19: READ CONFIGURATION REGISTER – B5h/85h

$C_x = 7 + A[MAX + 1]$
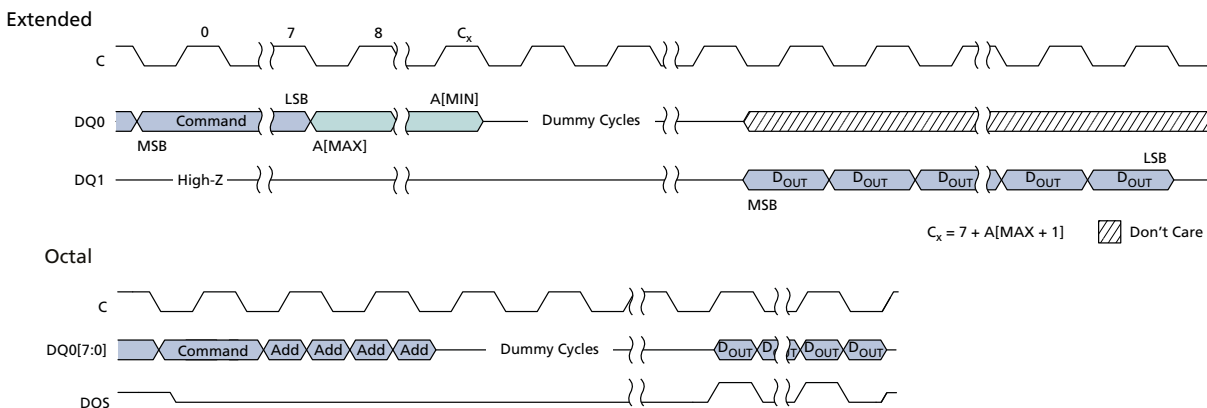
WRITE REGISTER Operations

Before a WRITE REGISTER command is initiated, the WRITE ENABLE command must be executed to set the write enable latch bit to 1. To initiate a command, S# is driven LOW and held LOW until the

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eighth bit of the last data byte has been latched in, after which it must be driven HIGH; for the WRITE NONVOLATILE CONFIGURATION REGISTER command. For the extended and octal SPI protocols respectively, input is on DQ0 and DQ[7:0], followed by the data bytes. If S# is not driven HIGH, the command is not executed, flag status register error bits are not set, and the write enable latch remains set to 1. The operation is self-timed and its duration is ^tW for WRITE STATUS REGISTER and ^tWNVCR for WRITE NONVOLATILE CONFIGURATION REGISTER.

Table 29: WRITE REGISTER Operations

Operation Name	Description/Conditions
WRITE STATUS REGISTER (01h)	The WRITE STATUS REGISTER command writes new values to status register bits 7:2, enabling software data protection. The status register can also be combined with the W# signal to provide hardware data protection. This command has no effect on status register bits 1:0.
WRITE NONVOLATILE CONFIGURATION REGISTER (B1h)	For the WRITE STATUS REGISTER and WRITE NONVOLATILE CONFIGURATION REGISTER commands, when the operation is in progress, the write in progress bit is set to 1. The write enable latch bit is cleared to 0, whether the operation is successful or not. The status register and flag status register can be polled for the operation status. When the operation completes, the write in progress bit is cleared to 0, whether the operation is successful or not.
WRITE VOLATILE CONFIGURATION REGISTER (81h)	Because register bits are volatile, change to the bits is immediate. Reserved bits are not affected by this command.

Figure 20: WRITE STATUS REGISTER – 01h
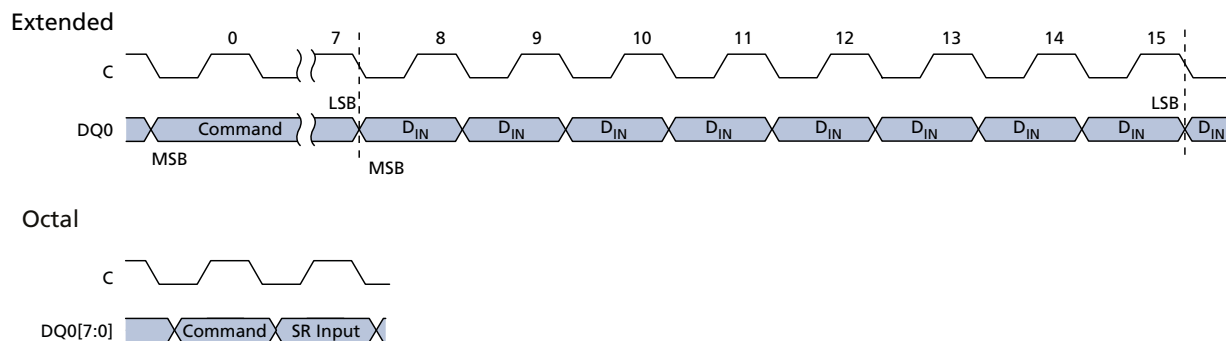
Note: 1. S# not shown.

Figure 21: WRITE CONFIGURATION REGISTER – B1h/81h
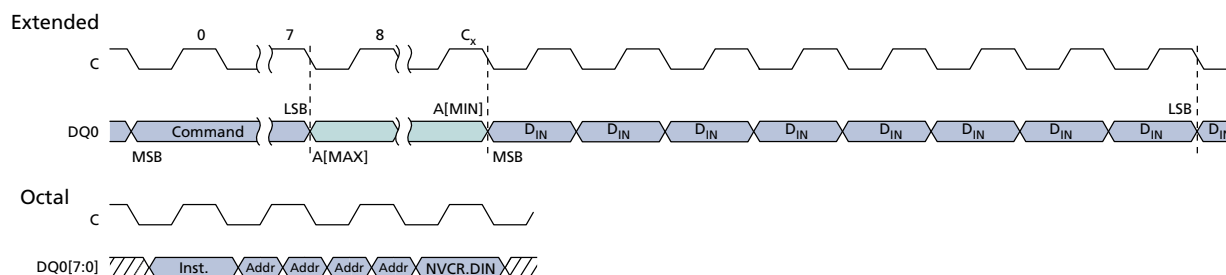
Notes: 1. S# not shown.
2. Requires 4 bytes of address if the device is configured to 4-byte address mode.

CLEAR FLAG STATUS REGISTER Operation

To initiate a command, S# is driven LOW. For the extended and octal SPI protocols respectively, input is on DQ0 and DQ[7:0]. The operation is terminated by driving S# HIGH at any time.

Table 30: CLEAR FLAG STATUS REGISTER Operation

Operation Name	Description/Conditions
CLEAR FLAG STATUS REGISTER (50h)	Resets the error bits (erase, program, and protection)

Figure 22: CLEAR FLAG STATUS REGISTER Timing
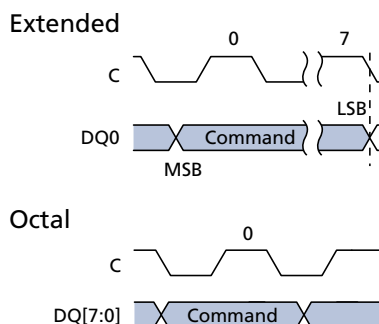
Note: 1. S# not shown.

PROGRAM Operations

Before a PROGRAM command is initiated, the WRITE ENABLE command must be executed to set the write enable latch bit to 1. To initiate a command, S# is driven LOW and held LOW until the eighth bit of the last data byte has been latched in, after which it must be driven HIGH. If S# is not driven HIGH, the command is not executed, flag status register error bits are not set, and the write enable latch remains set to 1. Each address bit is latched in during the rising edge of the clock. When a command is applied to a protected sector, the command is not executed, the write enable latch bit remains set to 1, and flag status register bits 1 and 4 are set. If the operation times out, the write enable latch bit is reset and the program fail bit is set to 1.

Note: The manner of latching data shown and explained in the timing diagrams ensures that the number of clock pulses is a multiple of one byte before command execution, helping reduce the effects of noisy or undesirable signals and enhancing device data protection.

Table 31: PROGRAM Operations

Operation Name	Description/Conditions
PAGE PROGRAM (02h)	A PROGRAM operation changes a bit from 1 to 0.
OCTAL INPUT FAST PROGRAM (82h)	When the operation is in progress, the write in progress bit is set to 1. The write enable latch bit is cleared to 0, whether the operation is
EXTENDED OCTAL INPUT FAST PROGRAM (C2h)	successful or not. The status register and flag status register can be polled for the operation status. When the operation completes, the write in progress bit is cleared to 0. An operation can be paused or resumed by the PROGRAM/ERASE SUSPEND or PROGRAM/ERASE RESUME command, respectively.
	If the bits of the least significant address, which is the starting address, are not all zero, all data transmitted beyond the end of the current page is programmed from the starting address of the same page. If the number of bytes sent to the device exceed the maximum page size, previously latched data is discarded and only the last maximum page-size number of data bytes are guaranteed to be programmed correctly within the same page. If the number of bytes sent to the device is less than the maximum page size, they are correctly programmed at the specified addresses without any effect on the other bytes of the same page. Due to its nature, Octal DDR operation requires bus transition in even number, therefore for program operation the following restrictions apply: – If there is a need to program from odd starting address, keep the even input address and the input data shall start with "FFh" – If there is a need to program with odd ending address, simply provide an extra data with "FFh" in the last falling edge of clock

4-BYTE PROGRAM Operations

Table 32: 4-BYTE PROGRAM Operations

Operation Name	Description/Conditions
4-BYTE PAGE PROGRAM (12h)	PROGRAM operations can be extended to a 4-bytes address range, with [A31:0] input during address cycle.
4-BYTE OCTAL INPUT FAST PROGRAM (84h)	Selection of the 3-byte or 4-byte address range can be enabled in two ways: through the nonvolatile configuration register or through the
4-BYTE EXTENDED OCTAL INPUT FAST PROGRAM (8Eh)	ENABLE 4-BYTE ADDRESS MODE/EXIT 4-BYTE ADDRESS MODE commands.

PROGRAM Operations Timings

Figure 23: PAGE PROGRAM – 02h/12h
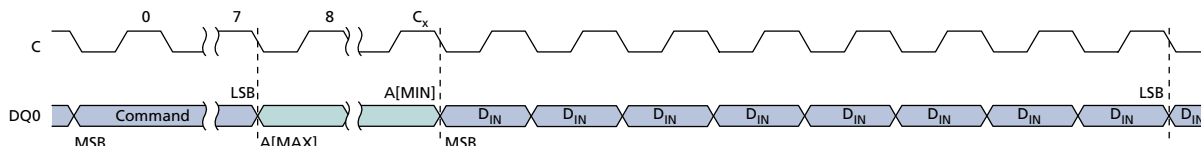
Notes: 1. Cx = 7 + (A[MAX]] + 1). Requires 32-bit address in 4-byte address configuration.

2. In octal DDR protocol, command, address, and data-out bits are transmitted on all eight data pins in DDR mode, and address is fixed with 4-byte.

3. S# not shown. The operation is self-timed, and its duration is ^{t}PP.

Figure 24: OCTAL INPUT FAST PROGRAM – 82h/84h
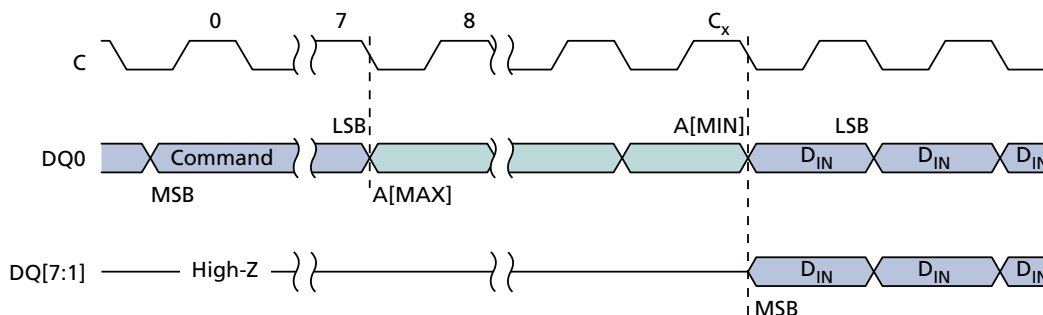
Notes: 1. Cx = 7 + (A[MAX]] + 1). Requires 32-bit address in 4-byte address configuration.

2. In octal DDR protocol, command, address, and data-out bits are transmitted on all eight data pins in DDR mode, and address is fixed with 4-byte.

3. S# not shown. The operation is self-timed, and its duration is ^{t}PP.

Figure 25: EXTENDED OCTAL INPUT FAST PROGRAM – C2h/8Eh
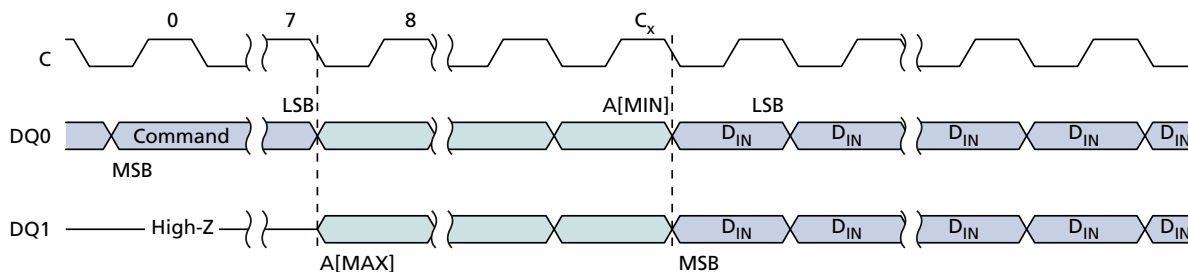

Notes: 1. Cx = 7 + (A[MAX]] + 1)/8. Requires 32-bit address in 4-byte address configuration.

2. In octal DDR protocol, command, address, and data-out bits are transmitted on all eight data pins in DDR mode, and address is fixed with 4-byte.

3. S# not shown. The operation is self-timed, and its duration is ^{t}PP.

ERASE Operations

An ERASE operation changes a bit from 0 to 1. Before any ERASE command is initiated, the WRITE ENABLE command must be executed to set the write enable latch bit to 1; if not, the device ignores the command and no error bits are set to indicate operation failure. S# is driven LOW and held LOW until the eighth bit of the last data byte has been latched in, after which it must be driven HIGH. The operations are self-timed, and duration is ^tSSE, ^tSE, or ^tBE according to command.

If S# is not driven HIGH, the command is not executed, flag status register error bits are not set, and the write enable latch remains set to 1. A command applied to a protected subsector is not executed. Instead, the write enable latch bit remains set to 1, and flag status register bits 1 and 5 are set.

When the operation is in progress, the program or erase controller bit of the flag status register is set to 0. In addition, the write in progress bit is set to 1. When the operation completes, the write in progress bit is cleared to 0. The write enable latch bit is cleared to 0, whether the operation is successful or not. If the operation times out, the write enable latch bit is reset and the erase error bit is set to 1.

The status register and flag status register can be polled for the operation status. When the operation completes, these register bits are cleared to 1.

Note: For all ERASE operations, noisy or undesirable signal effects can be reduced and device data protection enhanced by holding S# LOW until the eighth bit of the last data byte has been latched in; this ensures that the number of clock pulses is a multiple of one byte before command execution.

Table 33: ERASE Operations

Operation Name	Description/Conditions
SUBSECTOR ERASE (52h/20h)	Sets the selected subsector or sector bits to FFh. Any address within the subsector is valid for entry. Each address bit is latched in during the rising edge of the clock. The operation can be suspended and resumed by the PROGRAM/ERASE SUSPEND and PROGRAM/ERASE RESUME commands, respectively.
SECTOR ERASE (D8h)	
BULK ERASE (C7h/60h)	Sets the device bits to FFh. The command is not executed if any sector is locked. Instead, the write enable latch bit remains set to 1, and flag status register bits 1 and 5 are set.

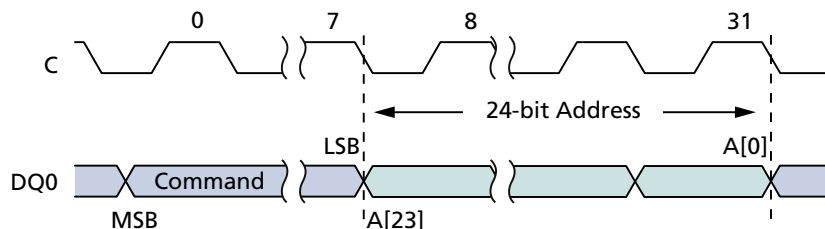**Figure 26: SUBSECTOR and SECTOR ERASE Timing**

Notes: 1. Requires 32-bit address in 4-byte address configuration.
2. In octal DDR protocol, command, address, and data-out bits are transmitted on all eight data pins in DDR mode, and address is fixed with 4-byte.
3. S# not shown. The operation is self-timed, and its duration is $^tSSE/^tSE$.

Figure 27: BULK ERASE Timing
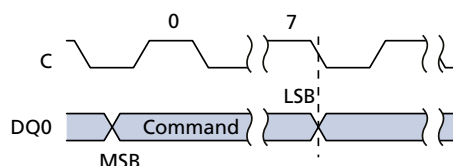
Notes: 1. In octal DDR protocol, command is transmitted on all eight data pins in DDR mode.
2. S# not shown. The operation is self-timed, and its duration is ^tBE.

SUSPEND/RESUME Operations

PROGRAM/ERASE SUSPEND Operations

A PROGRAM/ERASE SUSPEND command enables the memory controller to interrupt and suspend an array PROGRAM or ERASE operation within the program/erase latency. To initiate the command, S# is driven LOW, and the command code is input on DQn. The operation is terminated by the PROGRAM/ERASE RESUME command.

For a PROGRAM SUSPEND, the flag status register bit 2 is set to 1. For an ERASE SUSPEND, the flag status register bit 6 is set to 1.

After an erase/program latency time, the flag status register bit 7 is also set to 1, but the device is considered in suspended state once bit 7 of the flag status register outputs 1 with at least one byte output. In the suspended state, the device is waiting for any operation.

If the time remaining to complete the operation is less than the suspend latency, the device completes the operation and clears the flag status register bits 2 or 6, as applicable. Because the suspend state is volatile, if there is a power cycle, the suspend state information is lost and the flag status register powers up as 80h.

It is possible to nest a PROGRAM/ERASE SUSPEND operation inside a PROGRAM/ERASE SUSPEND operation just once. Issue an ERASE command and suspend it. Then issue a PROGRAM command and suspend it also. With the two operations suspended, the next PROGRAM/ERASE RESUME command resumes the latter operation, and a second PROGRAM/ERASE RESUME command resumes the former (or first) operation.

PROGRAM/ERASE RESUME Operations

To initiate the command, S# is driven LOW, and the command code is input on DQn. The operation is terminated by driving S# HIGH.

Table 34: SUSPEND/RESUME Operations

| Operation Name	Description/Conditions
PROGRAM SUSPEND (75h)	A READ operation is possible in any page except the one in a suspended state. Reading from a sector that is in a suspended state will output indeterminate data.
ERASE SUSPEND (75h)	A PROGRAM or READ operation is possible in any sector except the one in a suspended state. Reading from a sector that is in a suspended state will output indeterminate data. During a SUSPEND SUBSECTOR ERASE operation, reading an address in the sector that contains the suspended subsector could output indeterminate data. The device ignores a PROGRAM command to a sector that is in an erase suspend state; it also sets the flag status register bit 4 to 1 (program failure/protection error) and leaves the write enable latch bit unchanged. When the ERASE resumes, it does not check the new lock status of the WRITE VOLATILE LOCK BITS command.
PROGRAM RESUME (7Ah) ERASE RESUME (7Ah)	The status register write in progress bit is set to 1 and the flag status register program erase controller bit is set to 0. The command is ignored if the device is not in a suspended state. When the operation is in progress, the program or erase controller bit of the flag status register is set to 0. The flag status register can be polled for the operation status. When the operation completes, that bit is cleared to 1.

Notes: 1. See the Operations Allowed/Disallowed During Device States table.
2. When ERASE or PROGRAM operations are executed on stacked devices (1Gb and 2Gb), it is recommended that users not issue the PROGRAM/ERASE SUSPEND instruction after FSR.7 = 1 or SR.0 = 0 or time-out has been reached. In these cases, the Suspend flag would be set. Users can recover by issuing a PROGRAM/ERASE RESUME instruction.

Figure 28: PROGRAM/ERASE SUSPEND or RESUME Timing
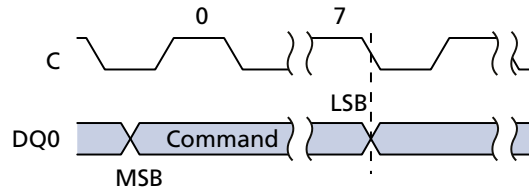
Notes: 1. In octal DDR protocol command is transmitted on all eight data pins.
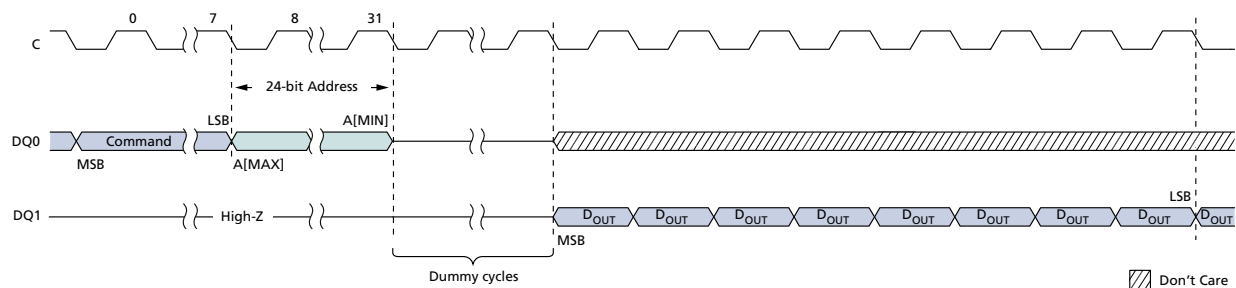   2. S# not shown.

ONE-TIME PROGRAMMABLE Operations

READ OTP ARRAY Command

To initiate a READ OTP ARRAY command, S# is driven LOW. The command code is input on DQ0, followed by address bytes and dummy clock cycles. Each address bit is latched in during the rising edge of C. Data is shifted out on DQ1, beginning from the specified address and at a maximum frequency of ^fC (MAX) on the falling edge of the clock. The address increments automatically to the next address after each byte of data is shifted out. There is no rollover mechanism; therefore, if read continuously, after location 0x40, the device continues to output data at location 0x40. The operation is terminated by driving S# HIGH at any time during data output.

Figure 29: READ OTP Command

Notes: 1. Requires 32-bit address in 4-byte address configuration.
2. In octal DDR protocol, command, address, and data-out bits are transmitted on all eight data pins in DDR mode, and address is fixed with 4-byte.
3. S# not shown.

PROGRAM OTP ARRAY Command

To initiate the PROGRAM OTP ARRAY command, the WRITE ENABLE command must be issued to set the write enable latch bit to 1; otherwise, the PROGRAM OTP ARRAY command is ignored, and flag status register bits are not set. S# is driven LOW and held LOW until the eighth bit of the last data byte has been latched in, after which it must be driven HIGH. The command code is input on DQ0, followed by address bytes and at least one data byte. Each address bit is latched in during the rising edge of the clock. When S# is driven HIGH, the operation, which is self-timed, is initiated; its duration is ^tPOTP. There is no rollover mechanism; therefore, after a maximum of 65 bytes are latched in the subsequent bytes are discarded.

PROGRAM OTP ARRAY programs, at most, 64 bytes to the OTP memory area and one OTP control byte. When the operation is in progress, the write in progress bit is set to 1. The write enable latch bit is cleared to 0, whether the operation is successful or not, and the status register and flag status register can be polled for the operation status. When the operation completes, the write in progress bit is cleared to 0.

If the operation times out, the write enable latch bit is reset and the program fail bit is set to 1. If S# is not driven HIGH, the command is not executed, flag status register error bits are not set, and the write enable latch remains set to 1. The operation is considered complete once bit 7 of the flag status register outputs 1 with at least one byte output.

The OTP control byte (byte 64) is used to permanently lock the OTP memory array.

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Table 35: OTP Control Byte (Byte 64)

Bit	Name	Settings	Description
0	OTP control byte	0 = Locked 1 = Unlocked (default)	Used to permanently lock the 64-byte OTP array. When bit 0 = 1, the 64-byte OTP array can be programmed. When bit 0 = 0, the 64-byte OTP array is read only. Once bit 0 has been programmed to 0, it can no longer be changed to 1. Program OTP array is ignored, the write enable latch bit remains set, and flag status register bits 1 and 4 are set.

Figure 30: PROGRAM OTP Command
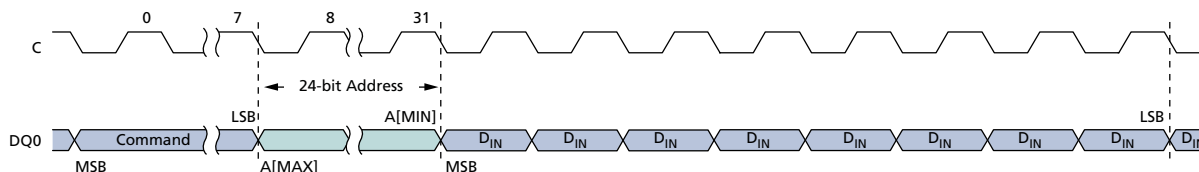
Notes: 1. Requires 32-bit address in 4-byte address configuration.
2. In octal DDR protocol, command, address, and data-out bits are transmitted on all eight data pins in DDR mode, and address is fixed with 4-byte.
3. S# not shown.

ADDRESS MODE Operations

ENTER and EXIT 4-BYTE ADDRESS MODE Command

To initiate these commands, S# is driven LOW, and the command is input on DQn.

Table 36: ENTER and EXIT 4-BYTE ADDRESS MODE Operations

Operation Name	Description/Conditions
ENTER 4-BYTE ADDRESS MODE (B7h)	The effect of the command is immediate. The default address mode is three bytes, and the device returns to the default upon exiting the 4-byte address mode.
EXIT 4-BYTE ADDRESS MODE (E9h)	

DEEP POWER-DOWN Operations

ENTER DEEP POWER-DOWN Command

To execute ENTER DEEP POWER-DOWN, S# must be driven HIGH after the eighth bit of the command code is latched in, after which, ^{t}DP time must elapse before the supply current is reduced to I_{CC2}. Any attempt to execute ENTER DEEP POWER-DOWN during a WRITE operation is rejected without affecting the operation.

In deep power-down mode, no device error bits are set, the WEL state is unchanged, and the device ignores all commands except RELEASE FROM DEEP POWER-DOWN, RESET ENABLE, RESET, hardware reset, and power-loss rescue sequence commands.

RELEASE FROM DEEP POWER-DOWN Command

To execute the RELEASE FROM DEEP POWER-DOWN command, S# is driven LOW, followed by the command code. Sending additional clock cycles on C while S# is driven LOW voids the command.

RELEASE FROM DEEP POWER-DOWN is terminated by driving S# HIGH. The device enters standby mode after S# is driven HIGH followed by a delay of ^{t}RDP. S# must remain HIGH during this time.

Table 37: DEEP POWER-DOWN Operations

Operation Name	Description/Conditions
ENTER DEEP POWER-DOWN (B9h)	The command is used to place the device in deep power-down mode for the lowest device power consumption, with device current reduced to I_{CC2}. This command can also be used as a software protection mechanism while the device is not in active use.
RELEASE FROM DEEP POWER-DOWN (ABh)	The command is used to exit from deep power-down mode. The device also exits deep power-down mode upon: A power-down, entering standby mode with the next power-up. A hardware or software reset operation, entering standby mode with a recovery time as specified in the AC Reset Specifications.

DEEP POWER-DOWN Timings

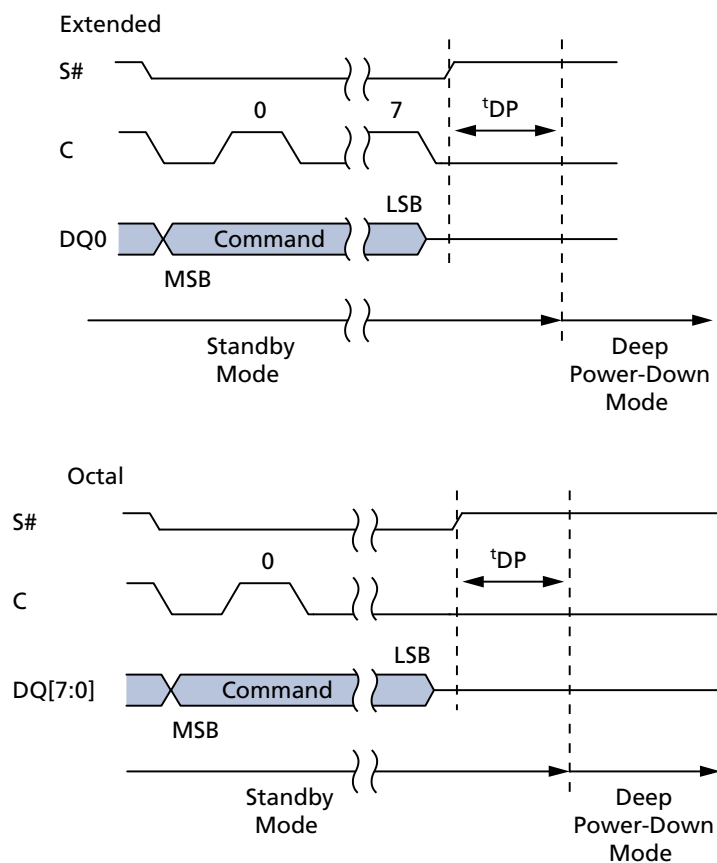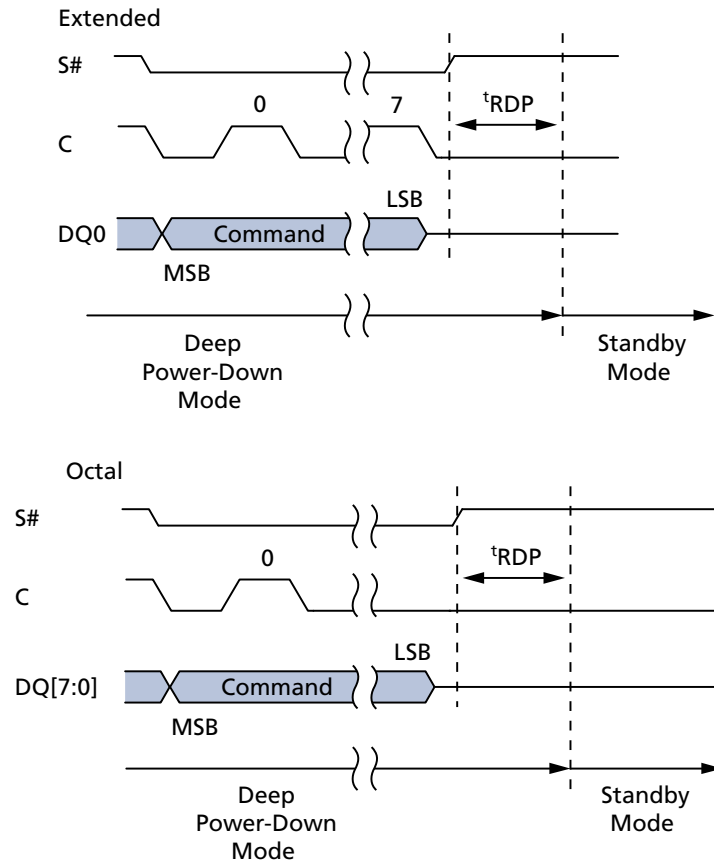**Figure 31: ENTER DEEP POWER-DOWN Timing**

Figure 32: RELEASE FROM DEEP POWER-DOWN Timing

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CYCLIC REDUNDANCY CHECK Operations

A CYCLIC REDUNDANCY CHECK (CRC) operation is a hash function designed to detect accidental changes to raw data and is used commonly in digital networks and storage devices such as hard disk drives. A CRC-enabled device calculates a short, fixed-length binary sequence, known as the CRC code or just CRC, for each block of data. CRC can be a higher performance alternative to reading data directly in order to verify recently programmed data. Or, it can be used to check periodically the data integrity of a large block of data against a stored CRC reference over the life of the product. CRC helps improve test efficiency for programmer or burn-in stress tests. No system hardware changes are required to enable CRC.

The CRC-64 operation follows the ECMA standard. The generating polynomial is:

$G(x) = x^{64} + x^{62} + x^{57} + x^{55} + x^{54} + x^{53} + x^{52} + x^{47} + x^{46} + x^{45} + x^{40} + x^{39} + x^{38} + x^{37} + x^{35} + x^{33}$

$+ x^{32} + x^{31} + x^{29} + x^{27} + x^{24} + x^{23} + x^{22} + x^{21} + x^{19} + x^{17} + x^{13} + x^{12} + x^{10} + x^9 + x^7 + x^4 + x + 1$

Note: The data stream sequence is from LSB to MSB and the default initial CRC value is all zero.

The device CRC operation generates the CRC result of the entire device or of an address range specified by the operation. Then the CRC result is compared with the expected CRC data provided in the sequence. Finally the device indicates a pass or fail through the bit #4 of FLAG STATUS REGISTER. If the CRC fails, it is possible to take corrective action such as verifying with a normal read mode or by rewriting the array data.

CRC operation supports CRC data read back when CRC check fails; the CRC data generated from the target address range or entire device will be stored in a dedicated register GPRR (general purpose read register) only when CRC check fails, and it can be read out through the GPRR read sequence with command 96h, least significant byte first. GPRR is reset to default all 0 at the beginning of the CRC operation, and so customer will read all 0 if CRC operation pass.

Note that the GPRR is a volatile register. It is cleared to all 0s on power-up and hardware/software reset. Read GPRR starts from the first location, when clocked continuously, will wrap after location 64.

The CYCLIC REDUNDANCY CHECK operation command sequences are shown in the tables below, for an entire die or for a selected range.

Table 38: CRC Command Sequence on Entire Device

Command Sequence		Description
Byte#	Data	
1	9Bh	Command code for interface activation
2	27h	Sub-command code for CRC operation
3	FFh	CRC operation option selection (CRC operation on entire device)
4	CRC[7:0]	1st byte of expected CRC value
5–10	CRC[55:8]	2nd to 7th byte of expected CRC value
11	CRC[63:56]	8th byte of expected CRC value
12	FFh	Data fill in only in DDR protocol
Drive S# HIGH		Operation sequence confirmed; CRC operation starts

Table 39: CRC Command Sequence on a Range

Command Sequence		Description
Byte#	Data	
1	9Bh	Command code for interface activation

Table 39: CRC Command Sequence on a Range (Continued)

Command Sequence		Description
Byte#	**Data**	
2	27h	Sub-command code for CRC operation
3	FEh	CRC operation option selection (CRC operation on a range)
4	CRC[7:0]	1st byte of expected CRC value
5 to 10	CRC[55:8]	2nd to 7th byte of expected CRC value
11	CRC[63:56]	8th byte of expected CRC value
12	Start Address [7:0]	Specifies the starting byte address for CRC operation
13 to 14	Start Address [23:8]	
15	Start Address [31:24]	
16	Stop Address [7:0]	Specifies the ending byte address for CRC operation
17 to 18	Stop Address [23:8]	
19	Stop Address [31:24]	
20	FFh	Data fill in only in DDR protocol
Drive S# HIGH		Operation sequence confirmed; CRC operation starts

State Table

The device can be in only one state at a time. Depending on the state of the device, some operations as shown in the table below are allowed (Yes) and others are not (No). For example, when the device is in the standby state, all operations except SUSPEND are allowed in any sector. For all device states except the erase suspend state, if an operation is allowed or disallowed in one sector, it is allowed or disallowed in all other sectors. In the erase suspend state, a PROGRAM operation is allowed in any sector except the one in which an ERASE operation has been suspended.

Table 40: Operations Allowed/Disallowed During Device States

Operation	Standby State	Program or Erase State	Subsector Erase Suspend or Program Suspend State	Erase Suspend State	Notes
READ	Yes	No	Yes	Yes	1
READ (status/flag status registers)	Yes	Yes	Yes	Yes	6
PROGRAM	Yes	No	No	Yes/No	2
ERASE (sector/subsector)	Yes	No	No	No	3
WRITE	Yes	No	No	No	4
WRITE	Yes	No	Yes	Yes	5
SUSPEND	No	Yes	No	No	7

Notes: 1. All READ operations except READ STATUS REGISTER and READ FLAG REGISTER. When issued to a sector or subsector that is simultaneously in an erase suspend state, the READ operation is accepted, but the data output is not guaranteed until the erase has completed.
2. All PROGRAM operations except PROGRAM OTP. In the erase suspend state, a PROGRAM operation is allowed in any sector (Yes) except the sector (No) in which an ERASE operation has been suspended.
3. Applies to the SECTOR ERASE or SUBSECTOR ERASE operation.
4. Applies to the following operations: WRITE STATUS REGISTER, WRITE NONVOLATILE CONFIGURATION REGISTER, PROGRAM OTP, and BULK ERASE.
5. Applies to the WRITE VOLATILE CONFIGURATION REGISTER, WRITE ENABLE, WRITE DISABLE, CLEAR FLAG STATUS REGISTER, or WRITE LOCK REGISTER operation.
6. Applies to the READ STATUS REGISTER or READ FLAG STATUS REGISTER operation.
7. Applies to the PROGRAM SUSPEND or ERASE SUSPEND operation.

XIP Mode

Execute-in-place (XIP) mode allows the memory to be read by sending an address to the device and then receiving the data on one or eight pins in parallel, depending on the customer requirements. XIP mode offers maximum flexibility to the application, saves instruction overhead, and reduces random access time.

## Activate or Terminate XIP Using Volatile Configuration Register

Applications that boot in SPI and must switch to XIP use the volatile configuration register. XIP provides faster memory READ operations by requiring only an address to execute, rather than a command code and an address.

To activate XIP requires two steps. First, enable XIP by setting volatile configuration register (byte 6). Next, drive the XIP confirmation bit to 0 during the next FAST READ operation. XIP is then active. Once in XIP, any command that occurs after S# is toggled requires only address bits to execute; a command code is not necessary, and device operations use the SPI protocol that is enabled. XIP is terminated by driving the XIP confirmation bit to 1. The device automatically resets the XIP volatile configuration register to FFh.

Activate or Terminate XIP Using Nonvolatile Configuration Register

Applications that must boot directly in XIP use the nonvolatile configuration register. To enable a device to power-up in XIP using this register, set nonvolatile configuration register (byte 6). Settings vary according to protocol, as explained in the Nonvolatile Configuration Register section. Because the device boots directly in XIP, after the power cycle, no command code is necessary. XIP is terminated by driving the XIP confirmation bit to 1.

Figure 33: XIP Mode Entered at Power-On
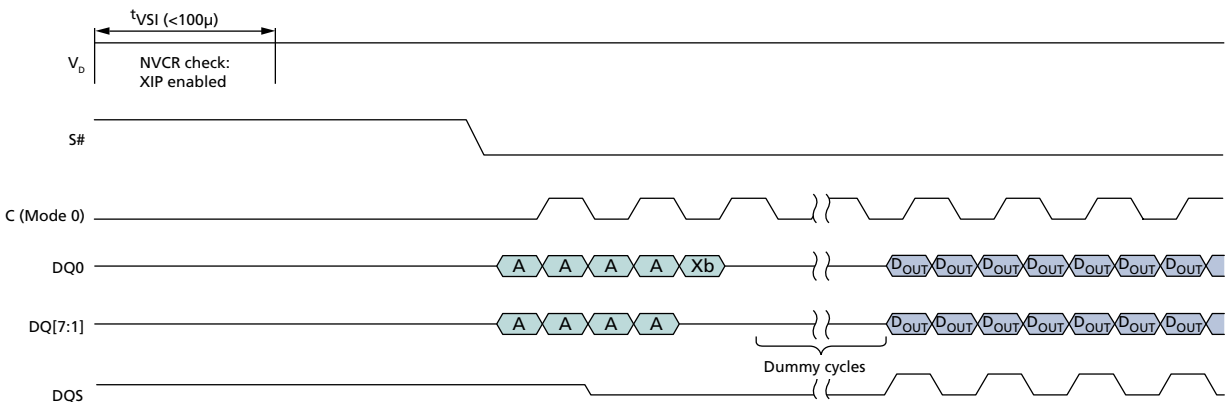
Notes: 1. Xb is the XIP confirmation bit and should be set as follows: 0 to keep XIP state; 1 to exit XIP mode and return to standard read mode.
2. Example of NVCR.06h = FEh; 8IOFR XIP in octal DDR protocol.

Figure 34: XIP Mode Entry by Volatile Configuration Register
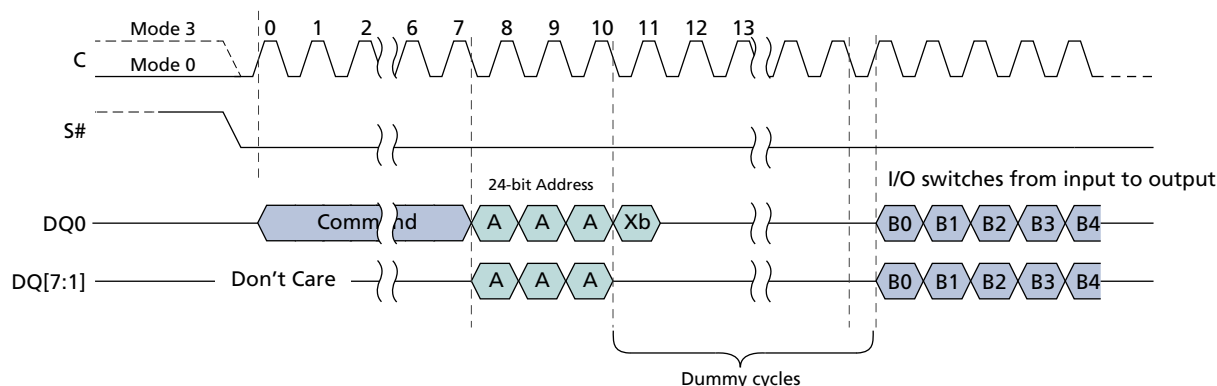
Note: 1. Xb is the XIP confirmation bit and should be set as follows: 0 to keep XIP state; 1 to exit XIP mode and return to standard read mode.

Confirmation Bit Settings Required to Activate or Terminate XIP

The XIP confirmation bit setting activates or terminates XIP after it has been enabled or disabled. This bit is the value on DQ0 during the first dummy clock cycle in the FAST READ operation. In octal I/O XIP mode, the values of DQ[7:1] during the first dummy clock cycle after the addresses are always "Don't Care."

Table 41: XIP Confirmation Bit

Bit Value	Description
0	Activates XIP: While this bit is 0, XIP remains activated.
1	Terminates XIP: When this bit is set to 1, XIP is terminated and the device returns to SPI.

Table 42: Effects of Running XIP in Different Protocols

Protocol	Effect
Extended I/O	A LOW pulse on RESET# pin resets XIP and the device to the state it was in previous to the last power-up, as defined by the nonvolatile configuration register.
Octal I/O	Values of DQ[7:1] during the first dummy clock cycle are "Don't Care."

Terminating XIP After a Controller and Memory Reset

The system controller and the device can become out of synchronization if, during the life of the application, the system controller is reset without the device being reset. In such a case, the controller can reset the memory to power-on reset by using RESET# pin.

The following sequences cause the controller to set the XIP confirmation bit to 1, thereby terminating XIP. However, it does not reset the device or interrupt PROGRAM/ERASE operations that may be in progress. After terminating XIP, the controller must execute RESET ENABLE and RESET MEMORY to implement a software reset and reset the device. It's required to have DQ0 equal to 1 for the situations listed here:

- 3 clock cycles within S# LOW (S# becomes HIGH before 4th clock cycle) +
- 4 clock cycles within S# LOW (S# becomes HIGH before 5th clock cycle) +
- 5 clock cycles within S# LOW (S# becomes HIGH before 6th clock cycle) +
- 25 clock cycles within S# LOW (S# becomes HIGH before 26th clock cycle) +
- 33 clock cycles within S# LOW (S# becomes HIGH before 34th clock cycle)

Power-Up and Power-Down

Power-Up and Power-Down Requirements

At power-up and power-down, the device must not be selected; that is, S# must follow the voltage applied on V_{CC} until V_{CC} reaches the correct values: $V_{CC,min}$ at power-up and V_{SS} at power-down.

To provide device protection and prevent data corruption and inadvertent WRITE operations during power-up, a power-on reset circuit is included. The logic inside the device is held to RESET while V_{CC} is less than the power-on reset threshold voltage shown here; all operations are disabled, and the device does not respond to any instruction. During a standard power-up phase, the device ignores all commands except READ STATUS REGISTER and READ FLAG STATUS REGISTER. These operations can be used to check the memory internal state. After power-up, the device is in standby power mode; the write enable latch bit is reset; the write in progress bit is reset; and the dynamic protection register is configured as (write lock bit, lock down bit) = (0,0).

Normal precautions must be taken for supply line decoupling to stabilize the V_{CC} supply. Each device in a system should have the V_{CC} line decoupled by a suitable capacitor (typically 100nF) close to the package pins. At power-down, when V_{CC} drops from the operating voltage to below the power-on-reset threshold voltage shown here, all operations are disabled and the device does not respond to any command.

When the operation is in progress, the program or erase controller bit of the status register is set to 0. To obtain the operation status, the flag status register must be polled. When the operation completes, the program or erase controller bit is cleared to 1. The cycle is complete after the flag status register outputs the program or erase controller bit to 1.

Note: If power-down occurs while a WRITE, PROGRAM, or ERASE cycle is in progress, data corruption may result.

V_{PPH} must be applied only when V_{CC} is stable and in the $V_{CC,min}$ to $V_{CC,max}$ voltage range.

Note: For additional details about how to properly apply and remove the power supply to the device, refer to TN-25-38: Power-Up, Power-Down, and Brownout Considerations on MT25Q, MT25T, and MT35X NOR Flash Memory

Figure 35: Power-Up Timing
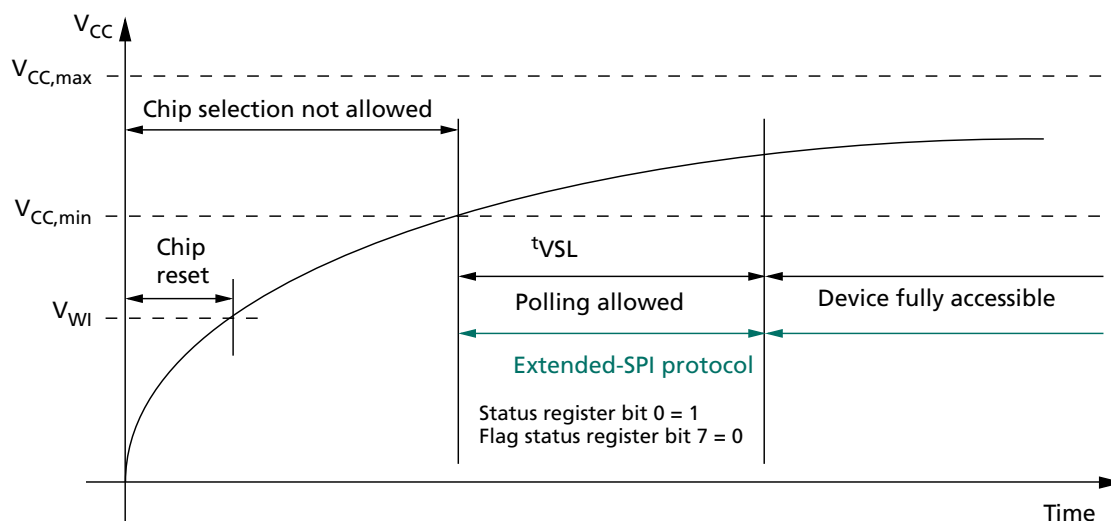
Notes: 1. ^{t}VSL polling has to be in extended-SPI protocol and SDR mode.

2. During ^{t}VSL period, output strength is default setting and DQS is disabled.

3. In a system that uses a fast V_{CC} ramp rate, current design requires a minimum 100µs after V_{CC} reaches ^{t}VWI, and before the polling is allowed, even though $V_{CC,min}$ is achieved.

Table 43: Power-Up Timing and V_{WI} Threshold

Note 1 applies to entire table

Symbol	Parameter	Min	Max	Unit	Notes
^{t}VSL	$V_{CC,min}$ to device fully accessible	–	300	µs	2, 3
V_{WI}	Write inhibit voltage	1.0	1.5	V	2

Notes: 1. When V_{CC} reaches $V_{CC,min}$, to determine whether power-up initialization is complete, the host can poll status register bit 0 or flag status register bit 7 only in extended SPI protocol because the device will accept commands only on DQ0 and output data only on DQ1. When the device is ready, the host has full access using the protocol configured in the nonvolatile configuration register. If the host cannot poll the status register in x1 SPI mode, it is recommended to wait ^{t}VSL before accessing the device.

2. Parameters listed are characterized only.

3. On the first power-up after an event causing a sub-sector ERASE operation interrupt (for example, due to power-loss), the maximum time for ^{t}VSL will be up to 4.5ms in case of 4KB subsector erase interrupt and up to 36ms in case of 32KB sub-sector erase interrupt; this accounts for erase recovery embedded operation.

Active, Standby, and Deep Power-Down Modes

When S# is LOW, the device is selected and in active power mode. When S# is HIGH, the device is deselected but could remain in active power mode until ongoing internal operations are completed. Then the device goes into standby power mode and device current consumption drops to I_{CC1}.

Deep power-down mode enbles users to place the device in the lowest power consumption mode, I_{CC2}. The ENTER DEEP POWER-DOWN command is used to put the device in deep power-down mode, and the RELEASE FROM DEEP POWER-DOWN command is used to bring the device out of deep power-down mode. Command details are in the Command Set table and the DEEP POWER-DOWN Operations section of this data sheet.

Power Loss and Interface Rescue

If a power loss occurs during a WRITE NONVOLATILE CONFIGURATION REGISTER command, after the next power-on, the device might begin in an undetermined state (XIP mode or an unnecessary protocol). If this occurs, a power loss recovery sequence must reset the device to a fixed state (default SPI protocol without XIP) until the next power-up.

If the controller and memory device get out of synchronization, the controller can follow an interface rescue sequence to reset the memory device interface to power-up to the last reset state (as defined by latest nonvolatile configuration register). This resets only the interface, not the entire memory device, and any ongoing operations are not interrupted.

After each sequence, the issue should be resolved definitively by running the WRITE NONVOLATILE CONFIGURATION REGISTER command again.

Note: The two steps in each sequence must be in the correct order.

First Step – Power Loss Recovery and Interface Rescue

The first step in both the power loss recovery and interface rescue sequences is DQ0 (PAD DATA) equal to 1 for the situations listed here:

- 3 clock cycles within S# LOW (S# becomes HIGH before 4th clock cycle) +
- 4 clock cycles within S# LOW (S# becomes HIGH before 5th clock cycle) +
- 5 clock cycles within S# LOW (S# becomes HIGH before 6th clock cycle) +
- 25 clock cycles within S# LOW (S# becomes HIGH before 26th clock cycle) +
- 33 clock cycles within S# LOW (S# becomes HIGH before 34th clock cycle)

Second Step – Power Loss Recovery

For power loss recovery, the second step in the sequence is exiting from present SPI protocol by using the following FFh sequence: DQ[7:0] equal to 1 for 8 clock cycles within S# LOW; S# becomes HIGH before 9th clock cycle. DQ[7:0] equal "1" should be driven on both edges of clock for 8 cycles with S# LOW. After this two-part sequence the default SPI protocol is active.

Second Step – Interface Rescue

For interface rescue, the second step in the sequence is exiting from present SPI protocol by using the following FFh sequence: DQ[7:0] equal to 1 for 16 clock cycles within S# LOW; S# becomes HIGH before 17th clock cycle. DQ[7:0] equal "1" should be driven on both edges of clock for 16 cycles with S# LOW. After this two-part sequence the device will be in the protocol defined by NVCR setting from latest power-up or reset.

Initial Delivery Status

The device is delivered as the following:

- Memory array erased: all bits are set to 1 (each byte contains FFh)
- All sectors un-protected
- Status register contains 00h (all status register bits are 0)
- Nonvolatile configuration register in default state

Absolute Ratings and Operating Conditions

Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only. Exposure to absolute maximum rating for extended periods may adversely affect reliability. Stressing the device beyond the absolute maximum ratings may cause permanent damage.

Table 44: Absolute Ratings

Symbol	Parameter	Min	Max	Units	Notes
T_{STG}	Storage temperature	–65	150	°C	–
T_{LEAD}	Lead temperature during soldering	–	See note 1	°C	–
V_{CC}	Supply voltage	–0.6	2.4	V	2
V_{PP}	Fast program voltage	–0.2	10	V	–
V_{IO}	I/O voltage with respect to ground	–0.6	$V_{CC} + 0.6$	V	2
V_{ESD}	Electrostatic discharge voltage (human body model)	–2000	2000	V	2, 3

Notes: 1. Compliant with JEDEC Standard J-STD-020C (for small-body, Sn-Pb or Pb assembly), RoHS, and the European directive on Restrictions on Hazardous Substances (RoHS) 2002/95/EU.
2. All specified voltages are with respect to V_{SS}. During infrequent, nonperiodic transitions, the voltage potential between V_{SS} and the V_{CC} may undershoot to –2.0V for periods less than 20ns, or overshoot to $V_{CC,max}$ + 2.0V for periods less than 20ns.
3. JEDEC Standard JESD22-A114A (C1 = 100pF, R1 = 1500, R2 = 500).

Table 45: Operating Conditions

Symbol	Parameter	Min	Max	Units
V_{CC}	Supply voltage	1.7	2.0	V
V_{PPH}	Supply voltage on V_{PP}	8.5	9.5	V
T_A	Ambient operating temperature (IT range)	–40	85	°C
T_A	Ambient operating temperature (AT range)	–40	105	°C
T_A	Ambient operating temperature (UT range)	–40	125	°C

Note: 1. V_{PP} must not remain at V_{PPH} for more than a total of 80 hours.

Table 46: I/O Capacitance

Symbol	Parameter	Min	Max	Units
$C_{IN/OUT}$	I/O capacitance DQ[7:0], DQS, RESET#	–	5	pF
C_{IN}	Input capacitance (other pins)	–	3	pF
$C_{IN/S\#}$	Input/Chip select	–	4	pF

Notes: 1. Verified in device characterization; not 100% tested. These parameters are not subject to a production test; they are verified by design and characterization. The capacitance is measured according to JEP147, "PROCEDURE FOR MEASURING INPUT CAPACITANCE USING A VECTOR NETWORK ANALYZER (VNA)," with VCC and VSS applied and all other pins floating (except the pin under test), $V_{BIAS} = V_{CC}/2$, TA = 25°C, frequency = 54 MHz.
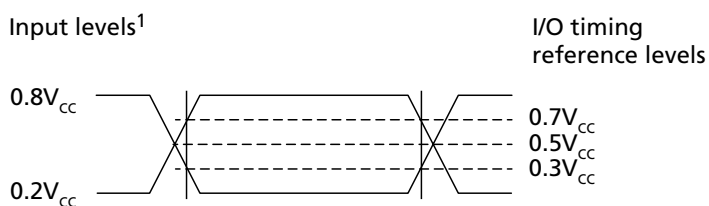2. Note 1 applies to entire table.

Table 47: AC Timing I/O Conditions

Symbol	Description	Data Transfer Rate	Min	Max	Units	Notes
C_L	Load capacitance	–	–	12	pF	1
–	Input rise and fall times	SDR and DDR	–	1.2	ns	–
–	Input pulse voltages	SDR and DDR	0.2 V_{CC} to 0.8 V_{CC}		V	–
–	Input timing reference voltages for Select#, Data-In, and RESET#	SDR and DDR	0.3 V_{CC} to 0.7 V_{CC}		V	–
–	Input timing reference voltages for Clock	SDR	0.3 V_{CC} to 0.7 V_{CC}		V	–
		DDR	V_{CC}/2			
–	Output timing reference voltages	SDR and DDR	V_{CC}/2		V	–

Note: 1. Output buffers are configurable by user.

Figure 36: AC Timing I/O Reference Levels

Input levels[1]

I/O timing
reference levels

0.8V_{CC}

0.2V_{CC}

0.7V_{CC}
0.5V_{CC}
0.3V_{CC}

DC Characteristics and Operating Conditions

Table 48: DC Current Characteristics and Operating Conditions

Note 1 applies to entire table

Parameter	Symbol	Test Conditions	Typ	Max	Unit	Notes
Input leakage current	I_{LI}	–	–	±2	µA	–
Output leakage current	I_{LO}	–	–	±2	µA	–
Standby current (IT range)	I_{CC1}	S = V_{CC}, V_{IN} = V_{SS} or V_{CC}	25	100	µA	2
Standby current (AT range)	I_{CC1}	S = V_{CC}, V_{IN} = V_{SS} or V_{CC}	25	200	µA	2
Standby current (UT range)	I_{CC1}	S = V_{CC}, V_{IN} = V_{SS} or V_{CC}	25	300	µA	2
Deep power-down current (IT range)	I_{CC2}	S = V_{CC}, V_{IN} = V_{SS} or V_{CC}	2	50	µA	3
Deep power-down current (AT range)	I_{CC2}	S = V_{CC}, V_{IN} = V_{SS} or V_{CC}	2	100	µA	3
Deep power-down current (UT range)	I_{CC2}	S = V_{CC}, V_{IN} = V_{SS} or V_{CC}	2	150	µA	3
Operating current (FAST READ EXTENDED I/O)	I_{CC3}	C = 0.1 V_{CC}/0.9V_{CC} at 133 MHz, DQ1 = open	–	16	mA	4
		C = 0.1 V_{CC}/0.9V_{CC} at 54 MHz, DQ1 = open	–	8	mA	4
Operating current (Octal SDR command)		C = 0.1 V_{CC}/0.9V_{CC} at 166 MHz, DQ = open	–	60	mA	–
Operating current (Octal DDR command)		C = 0.1 V_{CC}/0.9V_{CC} at 200 MHz, DQ = open	–	70	mA	–
Operating current (PROGRAM operations)	I_{CC4}	S# = V_{CC}	–	40	mA	5
Operating current (WRITE operations)	I_{CC5}	S# = V_{CC}	–	24	mA	–
Operating current (ERASE operations)	I_{CC6}	S# = V_{CC}	–	35	mA	–

Notes: 1. Currents are RMS unless noted. Typical values are at V_{CC} (1.8V); V_{IO} = 0V/V_{CC}; T_C = +25°C.

2. Standby current is an average calculated 5µs after S# deassertion and completion of any internal operation.

3. Deep power-down current is an average calculated during a 5ms time interval 100µs after completion of any internal operation.

4. Read current is an average calculated during a 1KB continuous READ operation without load, in a checkerboard pattern.

5. Program current is an average measured over a 256-byte data PROGRAM operation.

Table 49: DC Voltage Characteristics and Operating Conditions

Note applies to entire table

Parameter	Symbol	Conditions	Min	Max	Unit
Input low voltage (DC)	V_{IL}	–	–0.3	0.3 V_{CC}	V
Input low voltage (AC)		–	–0.3	0.2 V_{CC}	V
Input high voltage (DC)	V_{IH}	–	0.7 V_{CC}	V_{CC} + 0.3	V
Input high voltage (AC)		–	0.8 V_{CC}	V_{CC} + 0.3	V
Output low voltage	V_{OL}	I_{OL} = 1.6mA	–	0.15 × V_{CC}	V
Output high voltage	V_{OH}	I_{OH} = –100µA	0.85 × V_{CC}	–	V

Note: 1. V_{IL} can undershoot to –1.0V for periods less than 2ns; V_{IH} can overshoot to $V_{CC,max}$ + 1.0V for periods less than 2ns.

AC Characteristics and Operating Conditions

Table 50: AC Characteristics and Operating Conditions

Parameter	Symbol	Data Transfer Rate	Min	Typ	Max	Unit	Notes
Clock frequency for all commands other than READ	^{t}C	SDR	DC	–	166	MHz	–
		DDR	DC	–	200		
Clock frequency for READ command (03h or 13h)	^{t}R	SDR	DC	–	54	MHz	–
Clock HIGH time	^{t}CH	SDR	2.7	–	–	ns	2
		DDR	2.25	–	–		
Clock LOW time	^{t}CL	SDR	2.7	–	–	ns	2
		DDR	2.25	–	–		
Clock rise time (with respect to V_{IH}/V_{IL})	$^{t}CLCH$	SDR/DDR	1/1.2	–	–	V/ns	3, 4
Clock fall time (with respect to V_{IH}/V_{IL})	$^{t}CHCL$	SDR/DDR	1/1.2	–	–	V/ns	3, 4
S# active setup time (relative to clock)	$^{t}SLCH$	SDR/DDR	2.25	–	–	ns	–
S# not active hold time (relative to clock)	$^{t}CHSL$	SDR/DDR	2	–	–	ns	–
Data in setup time	$^{t}DVCH$	SDR/DDR	1.8/0.4	–	–	ns	–
	$^{t}DVCL$	DDR only	0.4	–	–	ns	–
Data in hold time	$^{t}CHDX$	SDR/DDR	1.8/0.4	–	–	ns	–
	$^{t}CLDX$	DDR only	0.4	–	–	ns	–
S# active hold time (relative to clock)	$^{t}CHSH$	SDR	2	–	–	ns	–
		DDR	2	–	–		
S# not active setup time (relative to clock)	$^{t}SHCH$	SDR	2	–	–	ns	–
		DDR	2	–	–	ns	
S# deselect time after a READ command	$^{t}SHSL1$	SDR/DDR	10	–	–	ns	–
S# deselect time after a nonREAD command	$^{t}SHSL2$	SDR/DDR	30	–	–	ns	–
Output disable time	$^{t}SHQZ$	SDR/DDR	–	–	6	ns	3
Data Valid Window	^{t}DVW	DDR	1.3	–	–	ns	–
Clock low to output valid (Cload = 12pf)	$^{t}CLQV$	SDR/DDR	–	–	6	ns	5
Clock high to output valid (Cload = 12pf)	$^{t}CHQV$	DDR	–	–	6	ns	5
Output hold skew	^{t}QHS	DDR	–	–	0.5	ns	–
DQS to last DQ valid	$^{t}DQSQ$	DDR	–	–	0.4	ns	–
DQS low after first clock	$^{t}CLQSL$	DDR	–	–	10	ns	6
S# to DQS High-Z	$^{t}SHQSZ$	DDR	–	–	6	ns	–
Output hold time	$^{t}CLQX$	SDR/DDR	1.3	–	–	ns	5
Output hold time	$^{t}CHQX$	DDR only	1.3	–	–	ns	5
CRC check time: main block	^{t}CRC	STR/DTR	–	3.7	–	ms	–
CRC check time: full chip (512Mb)	^{t}CRC	STR/DTR	–	1.9	–	s	–
Write protect setup time	$^{t}WHSL$	SDR/DDR	20	–	–	ns	7

Table 50: AC Characteristics and Operating Conditions (Continued)

Parameter	Symbol	Data Transfer Rate	Min	Typ	Max	Unit	Notes
Enhanced V_{PPH} HIGH to S# LOW	^tVPPHSL	SDR/DDR	200	–	–	ns	7
S# HIGH to deep power-down	^tDP	SDR/DDR	3	–	–	µs	–
S# HIGH to standby mode (DPD exit time)	^tRDP	SDR/DDR	30	–	–	µs	–
WRITE STATUS REGISTER cycle time	^tW	SDR/DDR	–	1.3	8	ms	–
WRITE NONVOLATILE CONFIGURATION REGISTER cycle time	^tWNVCR	SDR/DDR	–	0.2	1	s	–
WRITE PROTECTION MANAGEMENT REGISTER timing	^tPPMR	SDR/DDR	–	0.1	0.5	ms	–
Nonvolatile sector lock time	^tPPBP	SDR/DDR	–	0.1	2.8	ms	–
Program ASP register	^tASPP	SDR/DDR	–	0.1	0.5	ms	–
Program password	^tPASSP	SDR/DDR	–	0.2	0.8	ms	–
Erase nonvolatile sector lock array	^tPPBE	SDR/DDR	–	0.2	1	s	–
Page program time (256 bytes)	^tPP	SDR/DDR	–	120	1800	µs	8
Page program time with V_{PP} = VPPH (256 bytes)	^tPP	SDR/DDR	–	80	1800	µs	8
PROGRAM OTP cycle time (64 bytes)	^tPOTP	SDR/DDR	–	0.2	0.8	ms	–
Sector erase time	^tSE	SDR/DDR	–	0.2	1	s	–
4KB subsector erase time	^tSSE	SDR/DDR	–	20	400	ms	–
32KB subsector erase time	^tSSE	SDR/DDR	–	0.1	1	s	–
512Mb bulk erase time	^tBE	SDR/DDR	–	80	400	s	–

Notes: 1. Typical values given for T_A = 25 °C.

2. ^tCH + ^tCL must add up to $1/^fC$.

3. Value guaranteed by characterization; not 100% tested.

4. Expressed as a slew-rate.

5. The specification only applies when DQS is disabled. For "UT" parts, min value for tCLQX and tCHQX is 1.1ns

6. DQS will be driven with the first clock falling edge after S# LOW.

7. Only applicable as a constraint for a WRITE STATUS REGISTER command when STATUS REGISTER WRITE is set to 1.

8. Typical value is applied for pattern: 50% "0" and 50% "1."

AC Reset Specifications

Table 51: AC Reset Conditions

Note 1 applies to entire table

Symbol	Conditions	Min	Typ	Max	Unit	Notes
Parameter: Reset Pulse Width						
^{t}RLRH		50	–	–	ns	2
Parameter: Reset Recovery Time						
^{t}RHSL	Device deselected (S# HIGH) and is in XIP mode	40	–	–	ns	–
	Device deselected (S# HIGH) and is in standby mode	40	–	–	ns	–
	Commands are being decoded, any READ operations are in progress or any WRITE operation to volatile registers are in progress	40	–	–	ns	–
	Any device array PROGRAM/ERASE/SUSPEND/RESUME, PROGRAM OTP, NONVOLATILE SECTOR LOCK, and ERASE NONVOLATILE SECTOR LOCK ARRAY operations are in progress	30	–	–	µs	3
	While a WRITE STATUS REGISTER operation is in progress	–	^{t}W	–	ms	–
	While a WRITE NONVOLATILE CONFIGURATION REGISTER operation is in progress	–	^{t}WNVCR	–	ms	–
	On completion or suspension of a SUBSECTOR ERASE operation	–	^{t}SSE	–	s	–
	Device in deep power-down mode	–	^{t}RDP	–	ms	–
	While ADVANCED SECTOR PROTECTION PROGRAM operation is in progress	–	^{t}ASPP	–	ms	–
	While PASSWORD PROTECTION PROGRAM operation is in progress	–	^{t}PASSP	–	ms	–
Parameter: Software Reset Recovery Time						
^{t}SHSL3	Device deselected (S# HIGH) and is in standby mode	40	–	–	ns	–
	Any flash array PROGRAM/ERASE/SUSPEND/RESUME, PROGRAM OTP, NONVOLATILE SECTOR LOCK, and ERASE NONVOLATILE SECTOR LOCK ARRAY operations are in progress	30	–	–	µs	3
	While WRITE STATUS REGISTER operation is in progress	–	^{t}W	–	ms	–
	While a WRITE NONVOLATILE CONFIGURATION REGISTER operation is in progress	–	^{t}WNVCR	–	ms	–
	On completion/suspension of SUBSECTOR ERASE operation	–	^{t}SSE	–	s	–
	Device in deep power-down mode	–	^{t}RDP	–	ms	–
	While ADVANCED SECTOR PROTECTION PROGRAM operation is in progress	–	^{t}ASPP	–	ms	–
	While PASSWORD PROTECTION PROGRAM operation is in progress	–	^{t}PASSP	–	ms	–
Parameter: Chip Select HIGH to Reset HIGH						
^{t}SHRH	Chip must be deselected before reset is de-asserted	10	–	–	ns	–

Notes: 1. Values are guaranteed by characterization; not 100% tested.

2. The device reset is possible but not guaranteed if ^{t}RLRH < 50ns.

3. Only for AT and UT devices, value is 35µs.

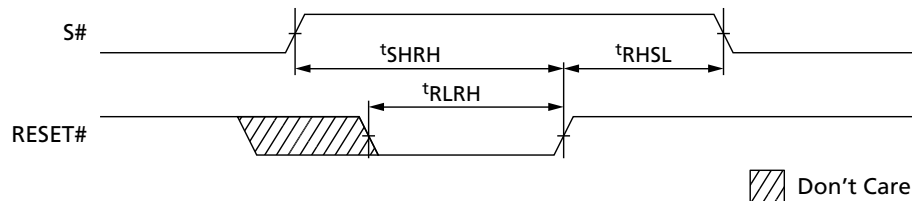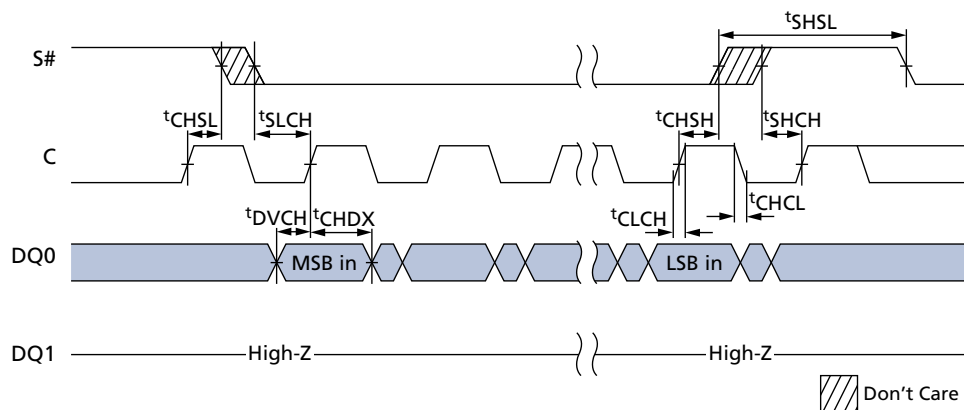**Figure 37: Reset AC Timing During PROGRAM or ERASE Cycle**

Figure 38: Serial Input Timing
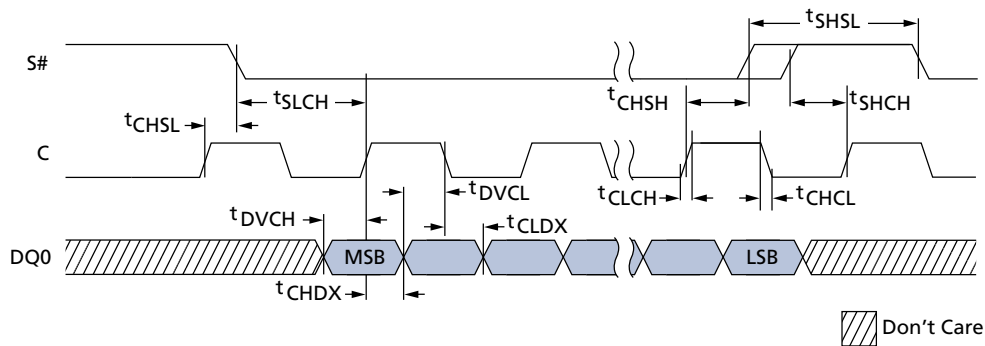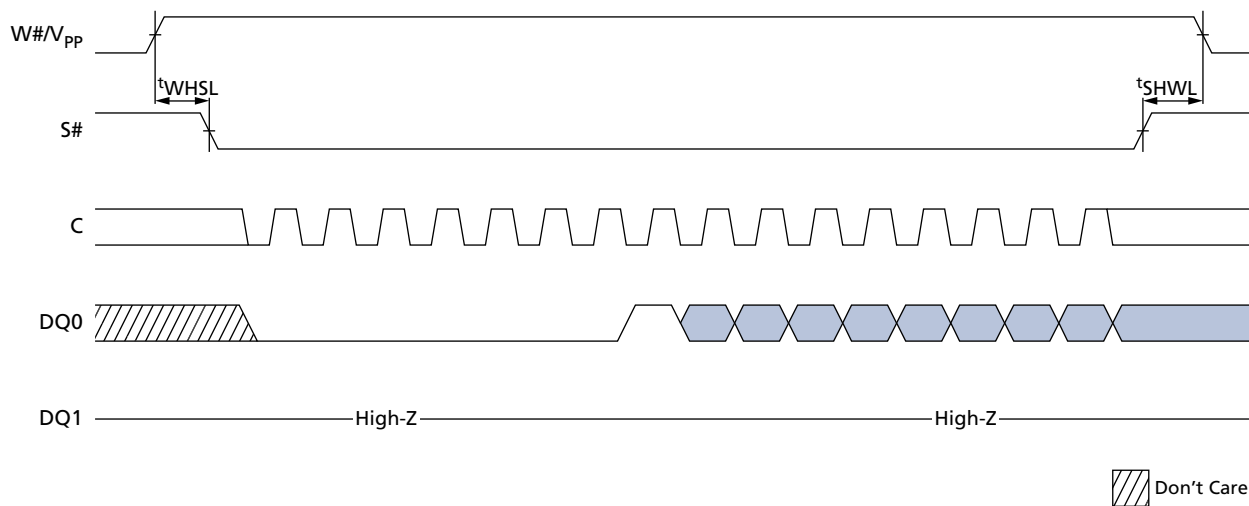

Figure 39: Serial Input Timing – DDR
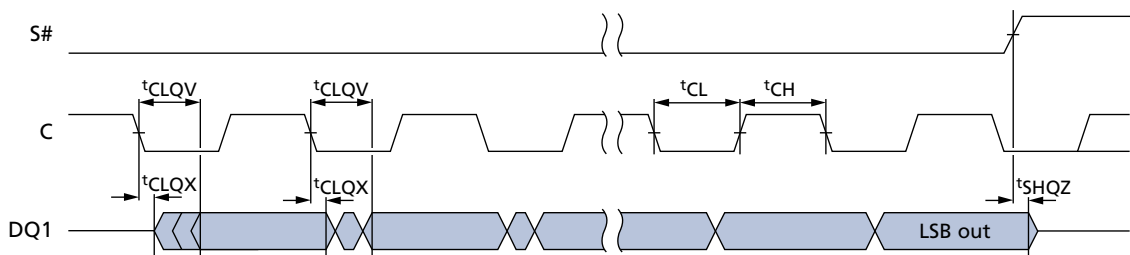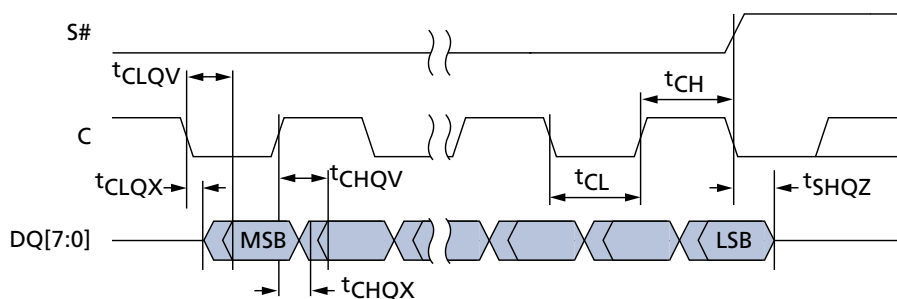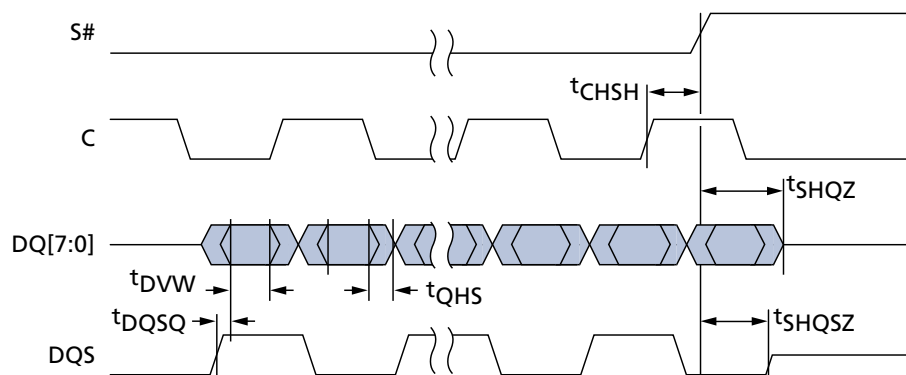
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Figure 40: Write Protect Setup and Hold During WRITE STATUS REGISTER Operation (SRWD = 1)

Figure 41: Output Timing – SDR

Figure 42: Output Timing – DDR

Figure 43: Output Timing – DDR with DQS

Note: 1. The device will be de-selected while clock is HIGH to get even counts of output data. Next DQ (or DQS) output could be observed if clock falling edge is received before S# goes HIGH.

Figure 44: V_{PPH} Timing
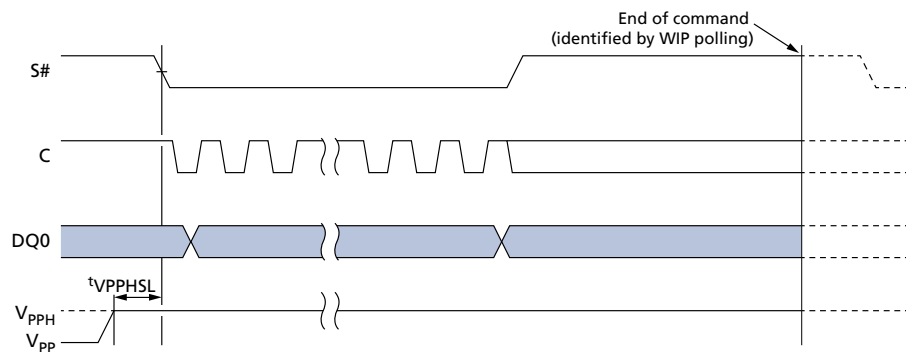
Program/Erase Specifications

Table 52: Program/Erase Specifications

Parameter	Condition	Typ	Max	Units	Notes
Erase to suspend	Sector erase or erase resume to erase suspend	150	–	µs	1
Program to suspend	Program resume to program suspend	5	–	µs	1
Subsector erase to suspend	Subsector erase or subsector erase resume to erase suspend	50	–	µs	1
Suspend latency	Program	7	30	µs	2, 3
Suspend latency	Subsector erase	15	30	µs	2, 4
Suspend latency	Erase	15	30	µs	4, 5

Notes: 1. Timing is not internally controlled.
2. Any READ command accepted.
3. For AT and UT devices only, value is 35µs
4. For UT devices only, value is 35µs
5. Any command except the following are accepted: SECTOR, SUBSECTOR, or BULK ERASE; WRITE STATUS REGISTER; WRITE NONVOLATILE CONFIGURATION REGISTER; and PROGRAM OTP.

Revision History

Rev. K – 10/23

- Fixed typo errors in the following tables:
  - Operations Allowed/Disallowed During Device States
  - AC Timing I/O Conditions
  - AC Characteristics and Operating Conditions

Rev. J – 02/23

- Fixed typo error in the Volatile Configuration Register paragraph
- Modified Serial Flash Discovery Parameter Data paragraph
- Clarified AC Timing I/O Conditions table
- Updated clock rise and fall time test condition in the AC Characteristics and Operating Conditions table

Rev. I – 12/18

- Data sheet version from preliminary to production

Rev. H – 05/18

- Added UT temperature range I_{cc1} and I_{cc2} values

Rev. G – 03/18

- Added UT temperature range
- Update Part Number Ordering Information figure
- Update notes for Nonvolatile Configuration Register table
- Added Active, Standby, and Deep Power-Down Modes
- Added DEEP POWER-DOWN Operations
- Added Clock Frequencies – SDR and DDR Read Codeword (32-Byte) Aligned table in Supported Clock Frequencies
- Updated AC Characteristics and Operating Conditions
- Updated Program/Erase Specifications
- Added Important Notes and Warnings section for further clarification aligning to industry standards

Rev. F – 06/17

- Updated Serial Flash Discovery Parameter Data section: Reviewed paragraph
- Added automotive I_{CC} currents in DC Current Characteristics and Operating Conditions table
- Changed document number from 09005aef864b038a to CCMTD-1725822587-3962

Rev. E – 12/16

- General review
- Changed XTRMFlash™ to **Xccela™** flash

Rev. D – 08/16

- Added Nonvolatile Lock Bit Security Register
- Added Protection Management Register
- Updated Device ID Data table in Device ID Data section

- Added general purpose read register notes to Command Definitions table
- Modified octal figure of READ STATUS REGISTER – 05h in READ REGISTER Operations section
- Added octal figure of WRITE CONFIGURATION REGISTER in WRITE REGISTER Operations section
- Added Initial Delivery Status
- Change I_{CC3}, I_{CC4}, and I_{CC5} values
- Added output hold time - $^{t}CVQX$ in AC Characteristics and Operating Conditions table

Rev. C – 01/16

- Removed SO16W package
- Added V_{PP} for program
- Changed status from Advanced to Preliminary

Rev. B – 10/15

- Updated language for XTRMFlash memory

Rev. A – 04/15

- Initial release